

# A SIPM MULTICHANNEL ASIC FOR HIGH RESOLUTION CHERENKOV TELESCOPES (SMART) DEVELOPED FOR THE PSCT CAMERA TELESCOPE

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Frontier Detectors for Frontier Physics  
15<sup>th</sup> Pisa meeting on advanced detectors  
La Biodola, Isola d'Elba



# The pSCT design

The Schwarzschild Couder Telescope for CTA

Dual-mirror medium size telescope:

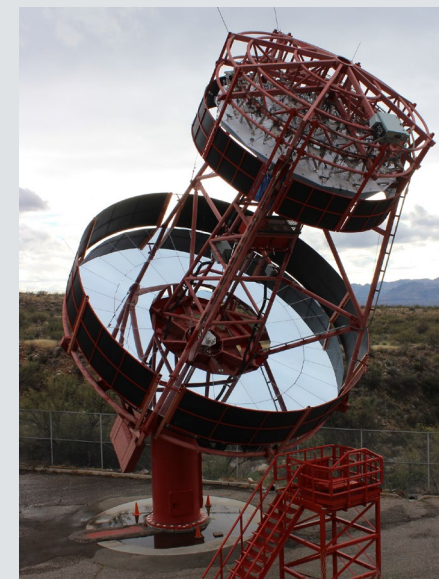
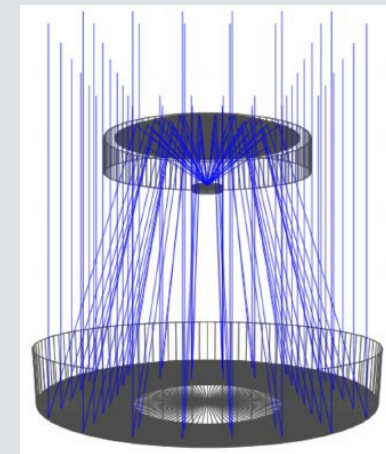
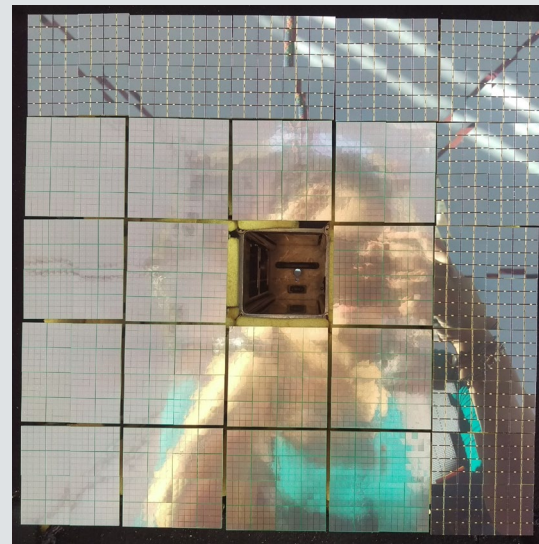
- Compensation of optical aberrations & de-magnification of images
- Compact (80 cm) and high-resolution camera with  $>11k$   $6 \times 6$  mm<sup>2</sup> SiPM pixels (8° FoV)

Current camera:

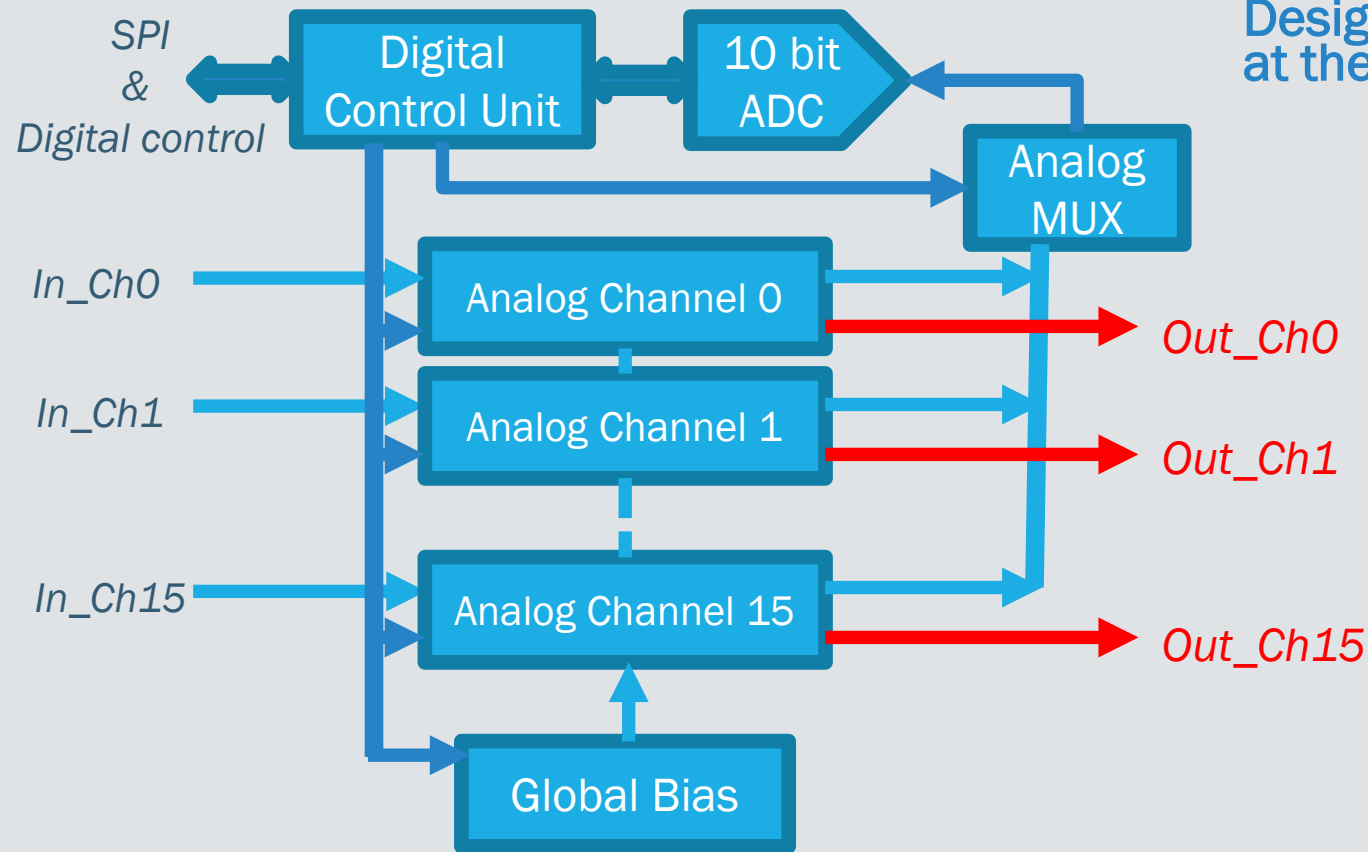
- 1.5k pixels only (2.7° FoV)
- FEE based on discrete pre-amplifier + TARGET-7

Upgraded camera (ongoing)

- Full camera ( $>11k$  pixels) with FBK NUV-HD SiPMs
- FEE based on SMART pre-amplifier + TARGET-C + T5TEA



# a SiPM Multichannel Asic for high Resolution Cherenkov Telescopes

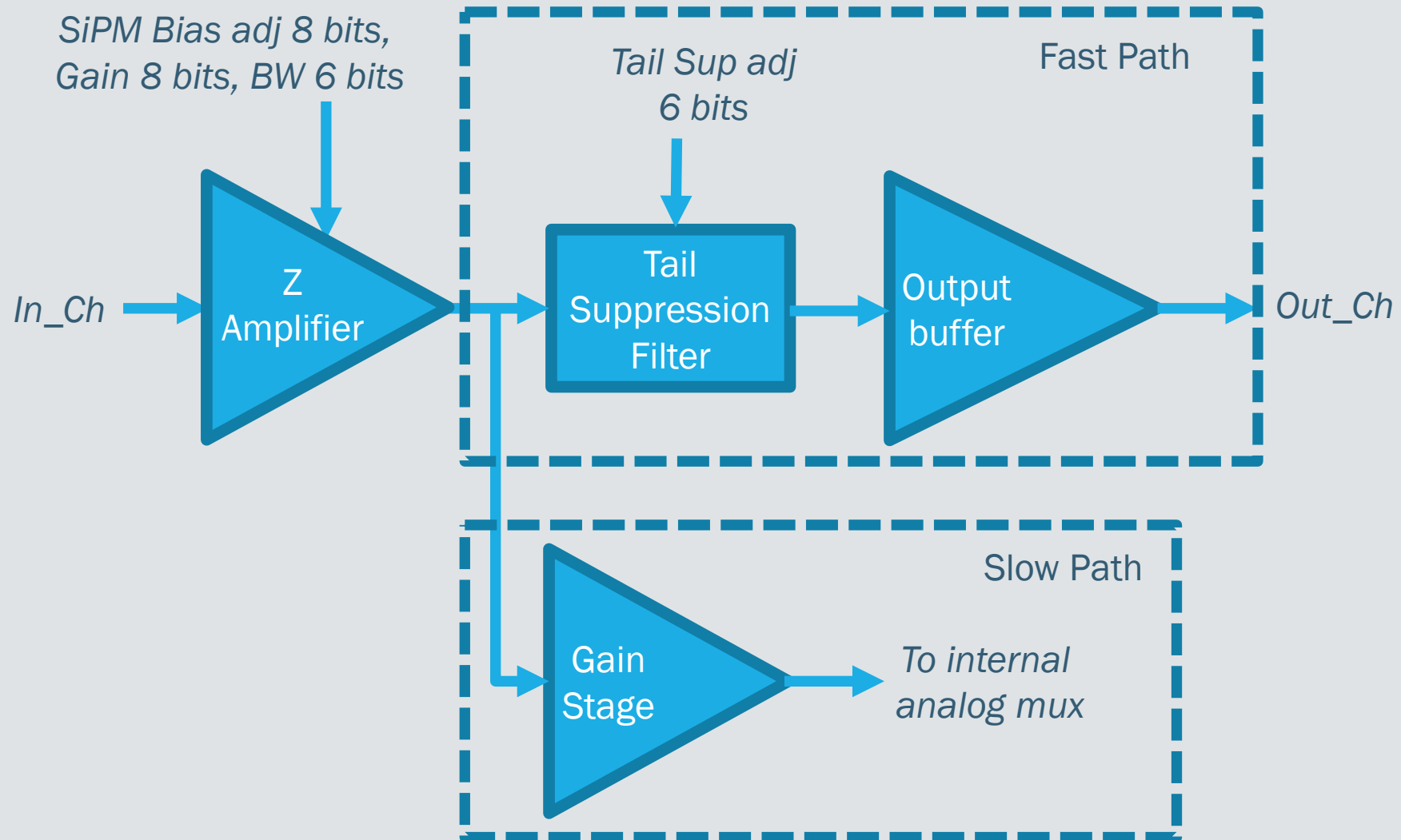


Designed by F. Licciulli & G. De Robertis  
at the Electronics CAD INFN Bari

Pre-amplifier designed for  
photon counting

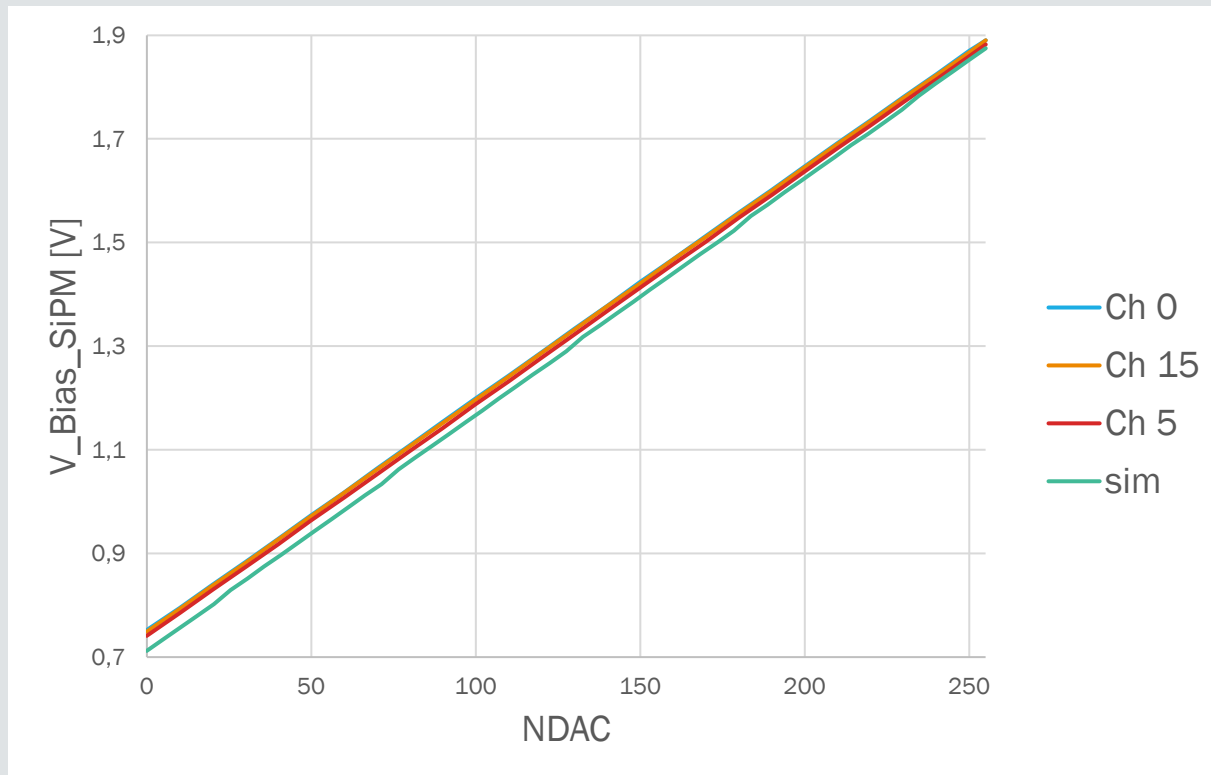
- 16-channel trans-impedance amplifier
- 20-bit global adjustment: gain (8 bits), bandwidth (6 bits), PZ (6 bits)
- 8-bit DAC for SiPM bias fine tuning (1 DAC/ch)
- Slow monitoring of SiPM current (10-bit ADC)
- 1 MHz LVDS SPI interface
- 600 mV dynamic range

# Channel architecture



# DAC Bias voltage

- Measurement of the channel input voltage as a function of the DAC configuration



The SiPM bias voltage is:

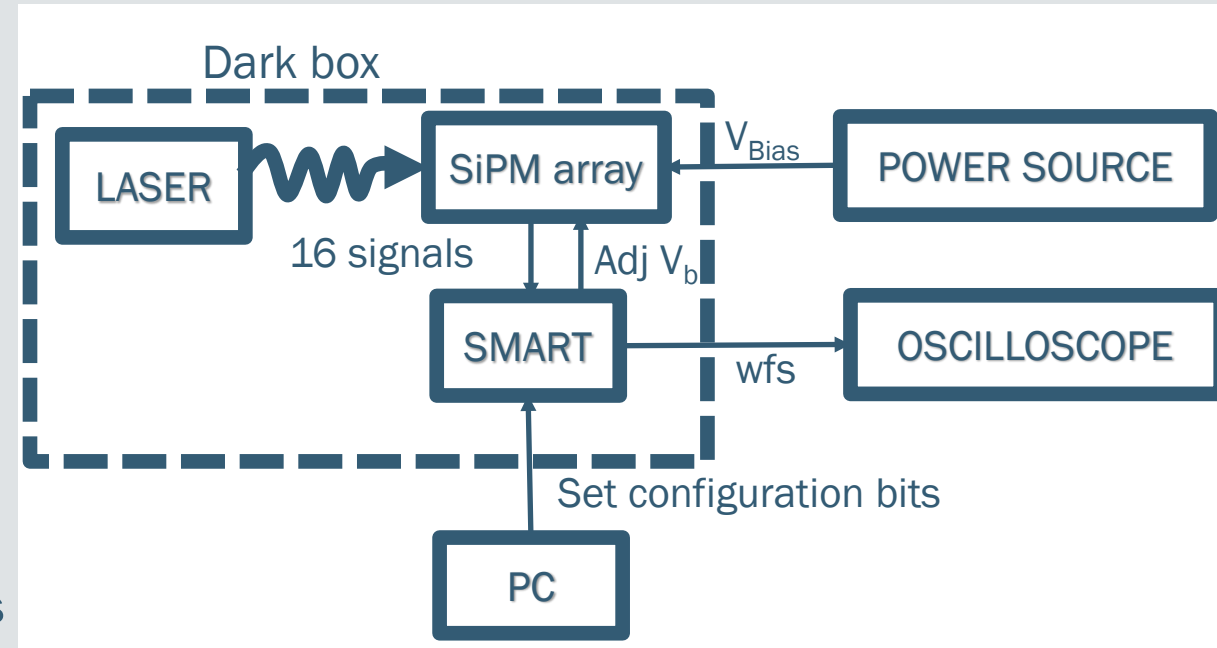
$$V_{bias, SiPM} = V_{external} - V_{DAC, channel}$$

$$V_{DAC} \in [0.75, 1.9] V$$

$V_{DAC}$  range is approximately 1.2 V

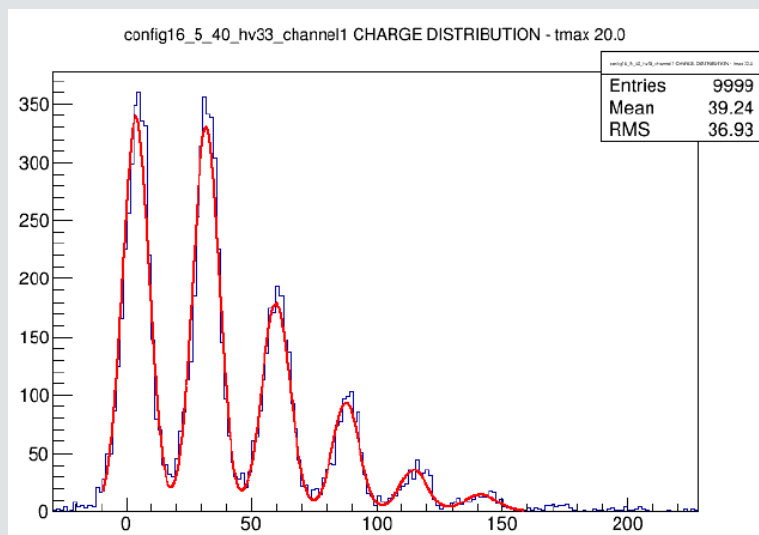
# SMART characterization

- We measured gain, signal-to-noise ratio and pulse width as a function of configuration bits
- 3 parameters changed
  - $R$  : gain resistance
  - $C$  : filtering capacitance
  - $PZ$ : pole zero cancellation
- External PZ fixed with discrete components
- Tests at different bias voltage ( $V_{Bias} = 33, 35, 37$  V)
- We placed a mask on the SiPM array in order to reduce any cross-talk contribution



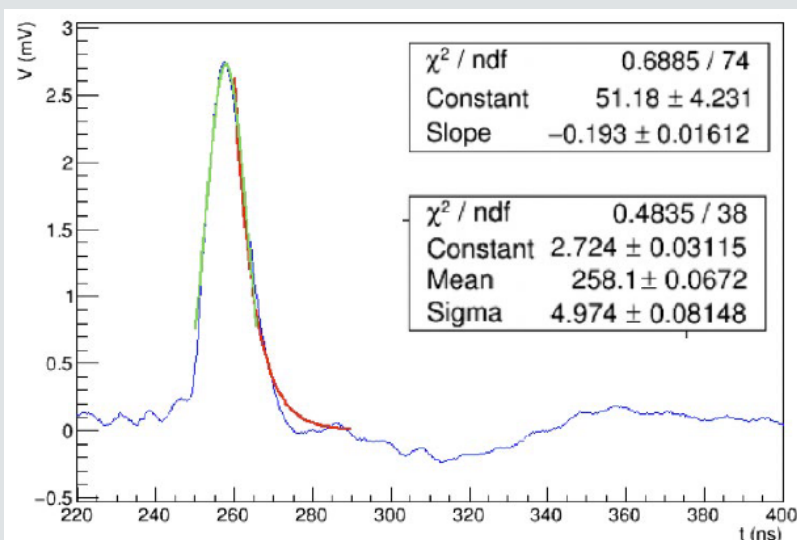
# SMART characterization

SMART performances tested with FBK NUV-HD 6x6mm<sup>2</sup> SiPM (HV=33V)



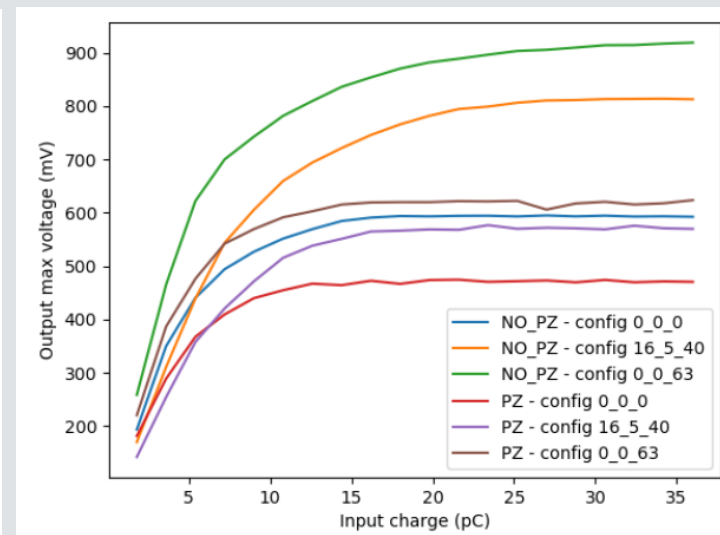
Charge distribution (cfg 16,5,40):

- Gain = 2.41 mV/pe
- SNR\_amp = 4.93
- SNR\_chg = 5.19



Output pulse (cfg 16,5,40):

- FWHM = 11.69 ns
- Tau\_dec = 5.81 ns

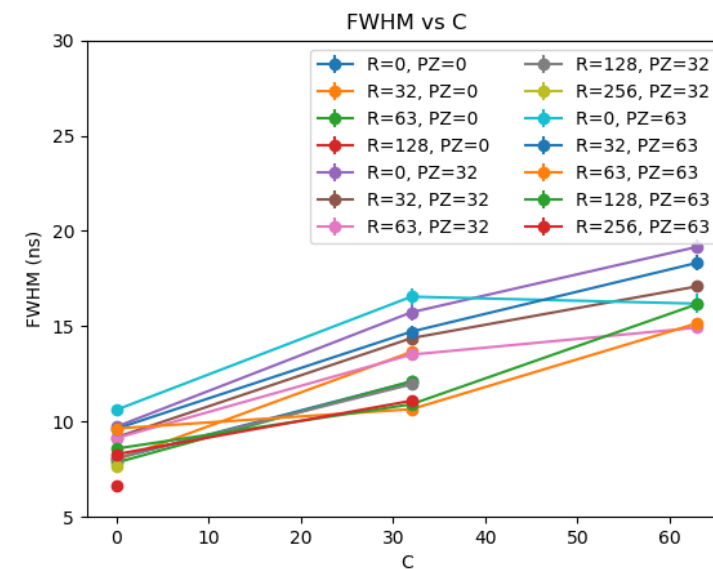
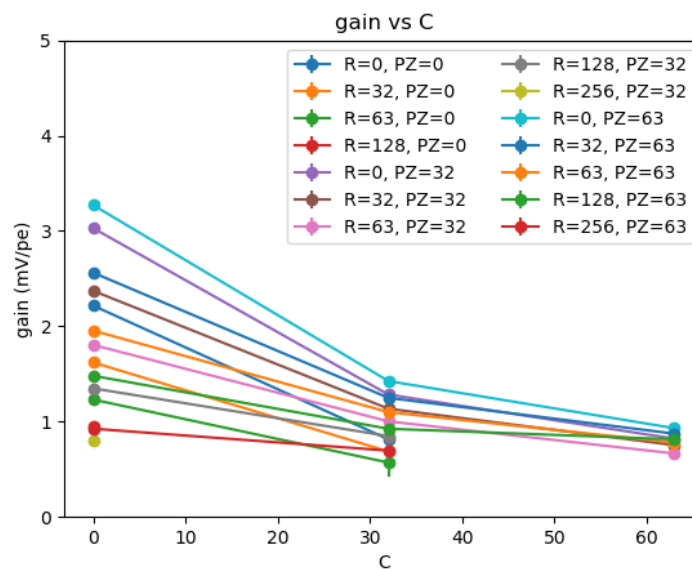
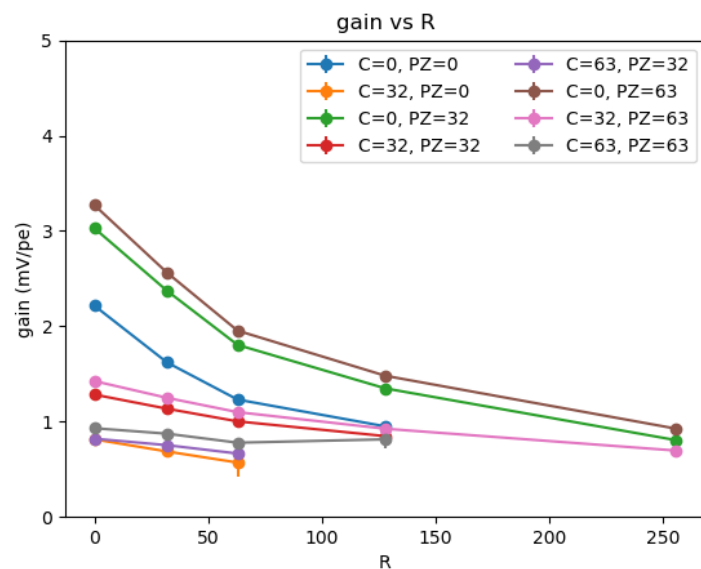


Output dynamic range

- 900 mV without ext. PZ
- 600 mV with ext. PZ

# Global configuration – Summary

$$V_{\text{Bias}} = 33 \text{ V}$$



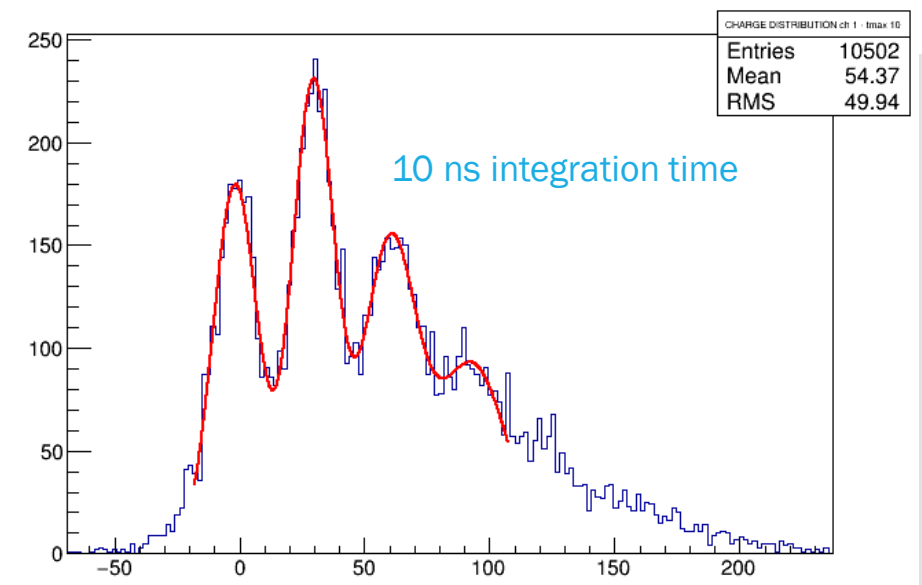
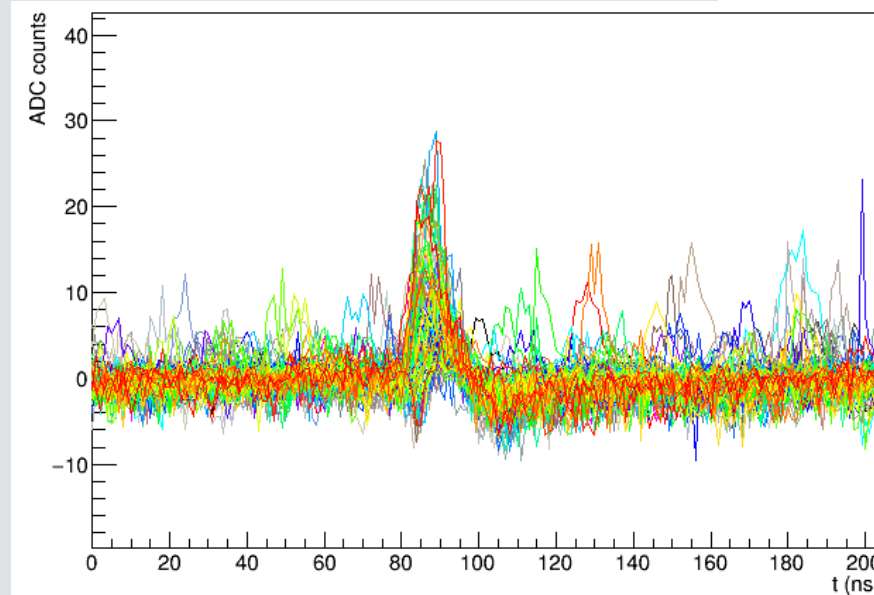
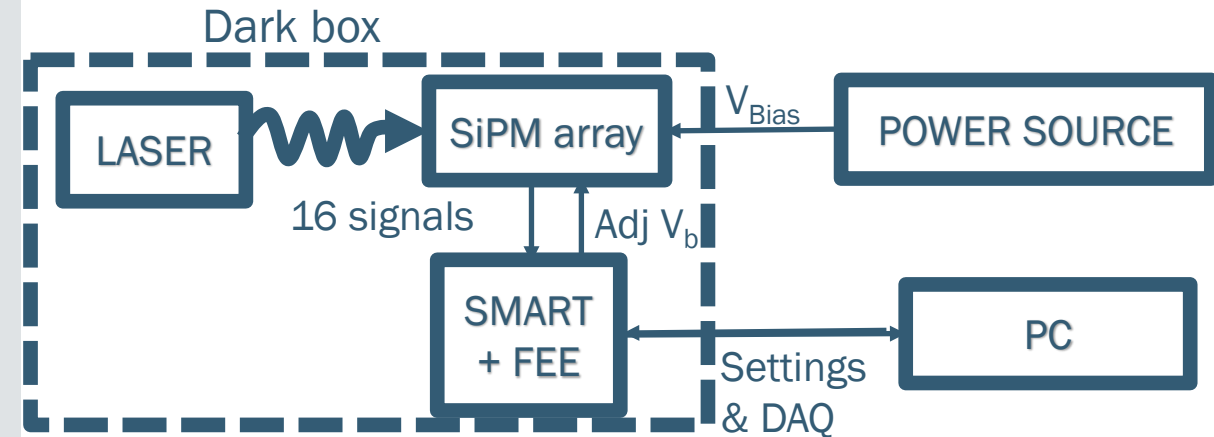
Gain depends mainly on R & C  
FWHM depends on C & PZ

Gain: [0.57 , 3.27] mV/pe  
FWHM: [7.68, 19.16] ns  
Tau : [3.0, 19.58] ns



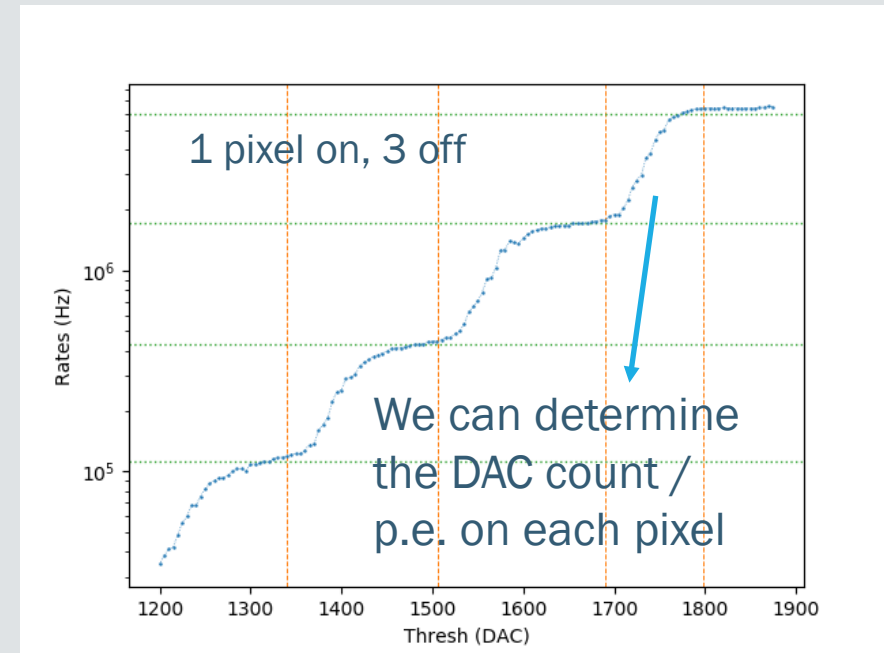
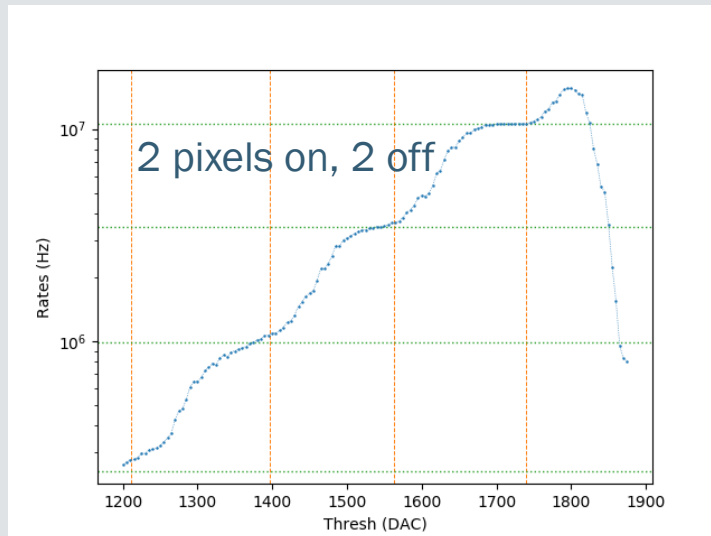
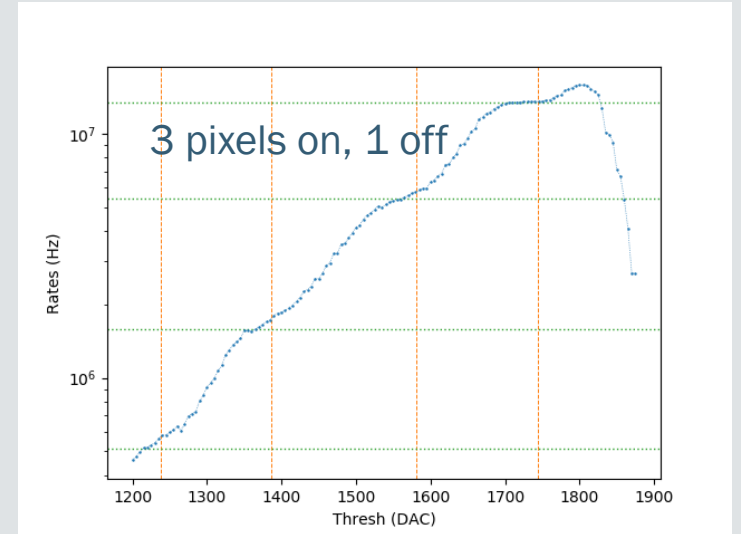
# Complete FEE measurements

- Laser far away from SiPM arrays, diffusing lens placed in between to achieve uniform illumination
- SiPM arrays + SMART + FEE module
- 10s acquisition time (about 10k wfs)



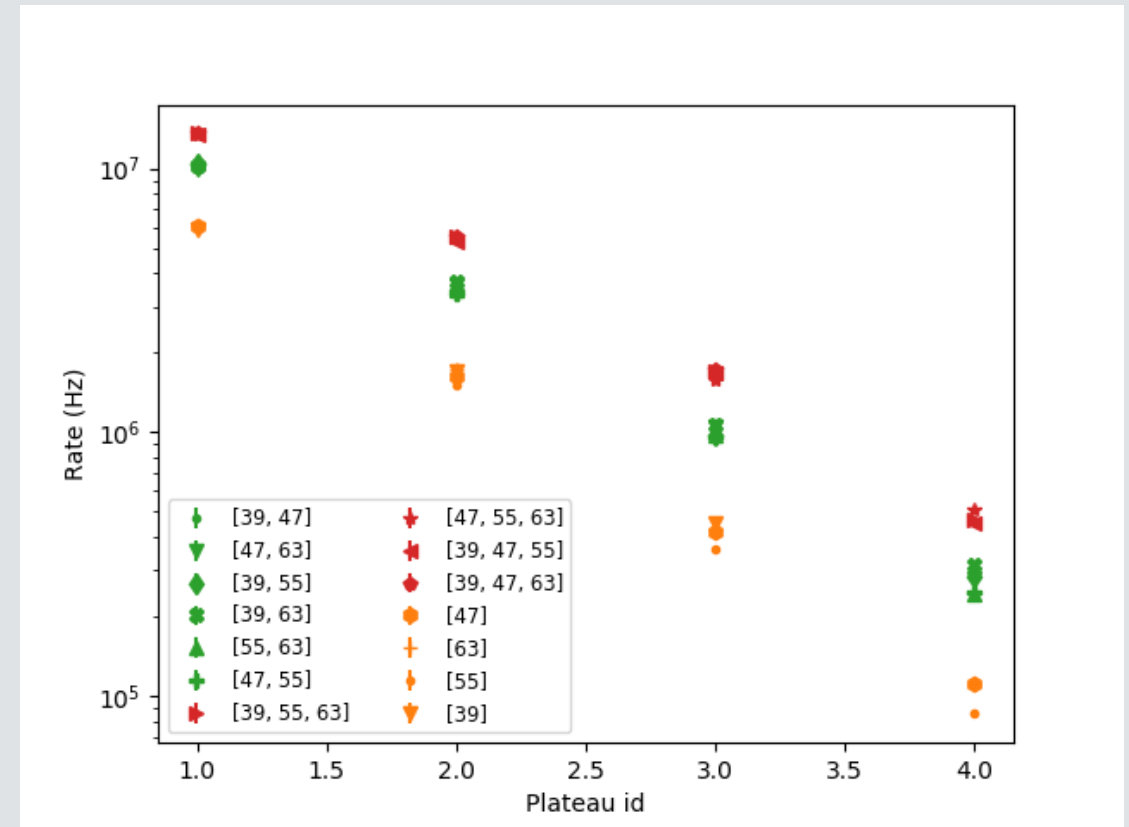
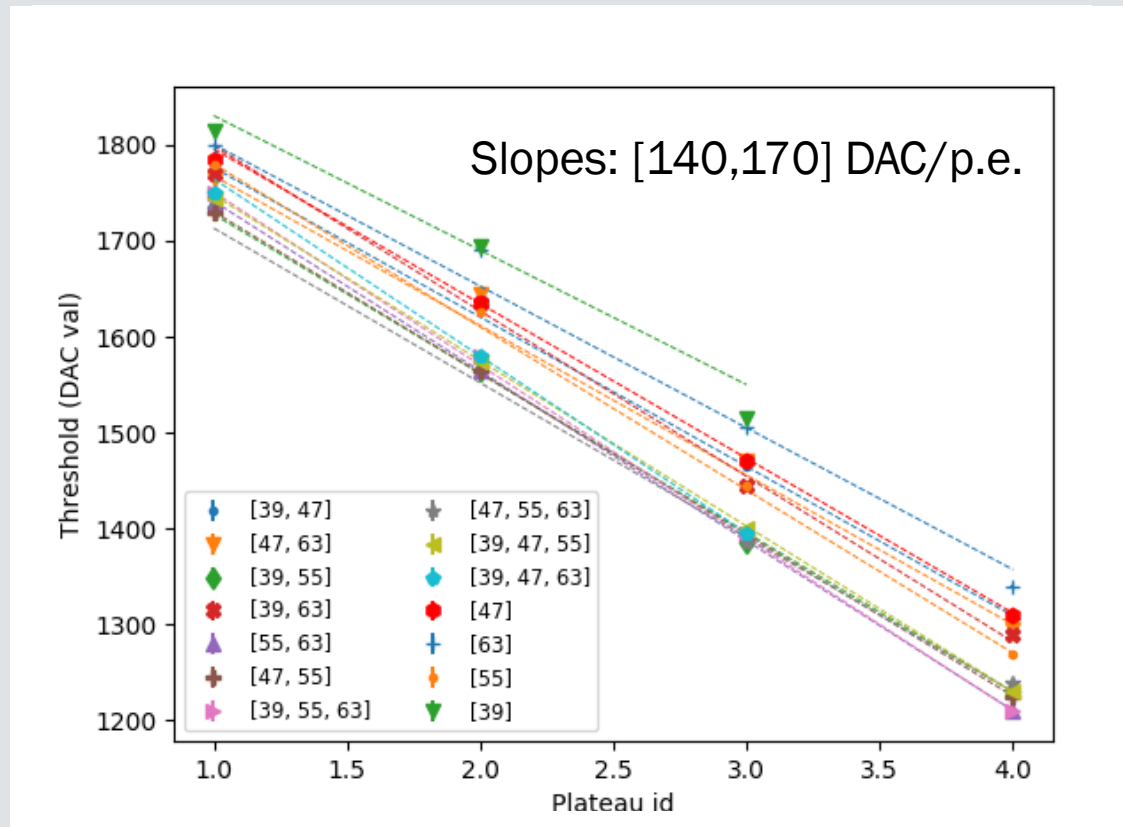
# Rate scan

- Auto-trigger of FEE on groups of 4 pixels
- We performed a scan in threshold value trigger on one group
  - *We performed the scan disabling 1, 2 and 3 pixels (i.e., triggering on 3, 2, and 1 pixels) using SMART registers*
- We looked for single p.e. plateaux in the rates



# Rate scan results

Rate scan tests are very useful to find single p.e. thresholds for individual pixels



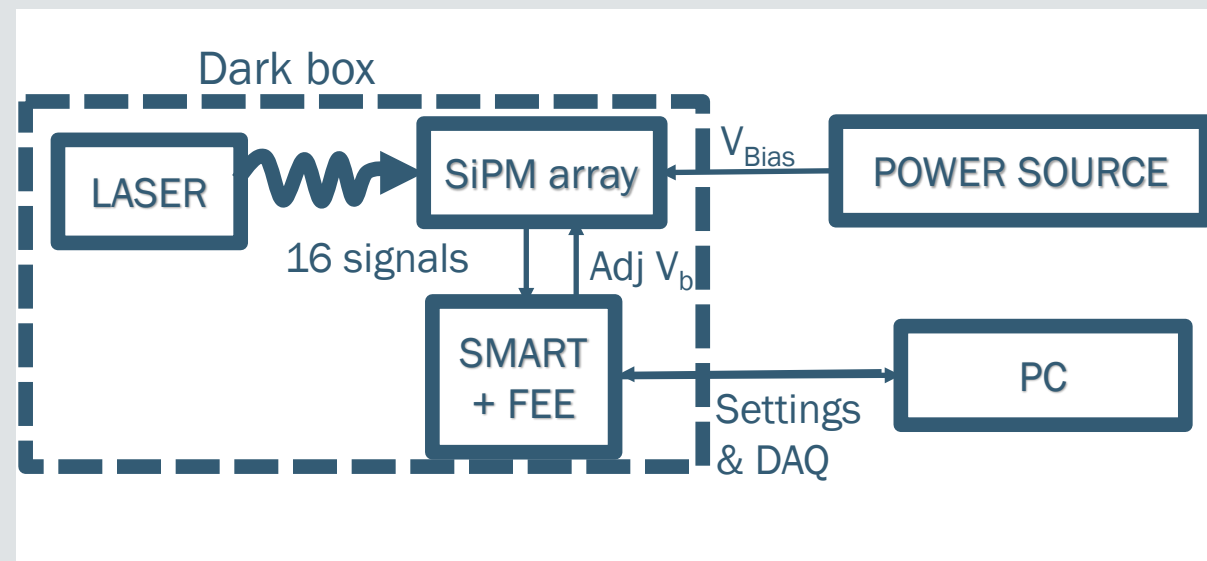
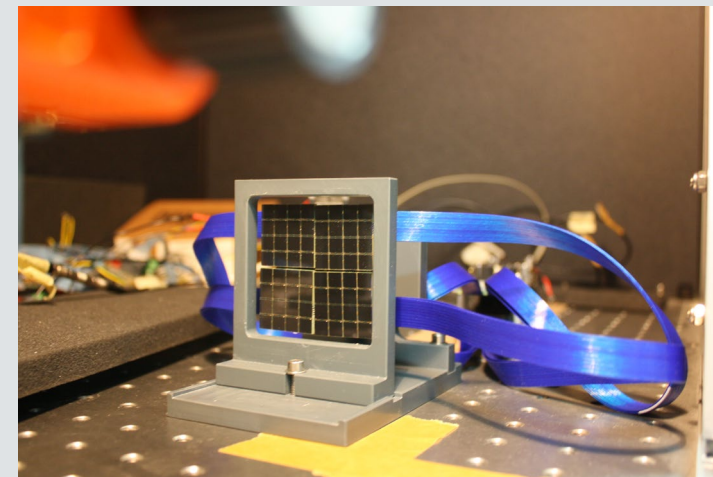
# SMART quality control

About 750 ASICs produced

We want to test the main features of the SMART to check basic functionalities:

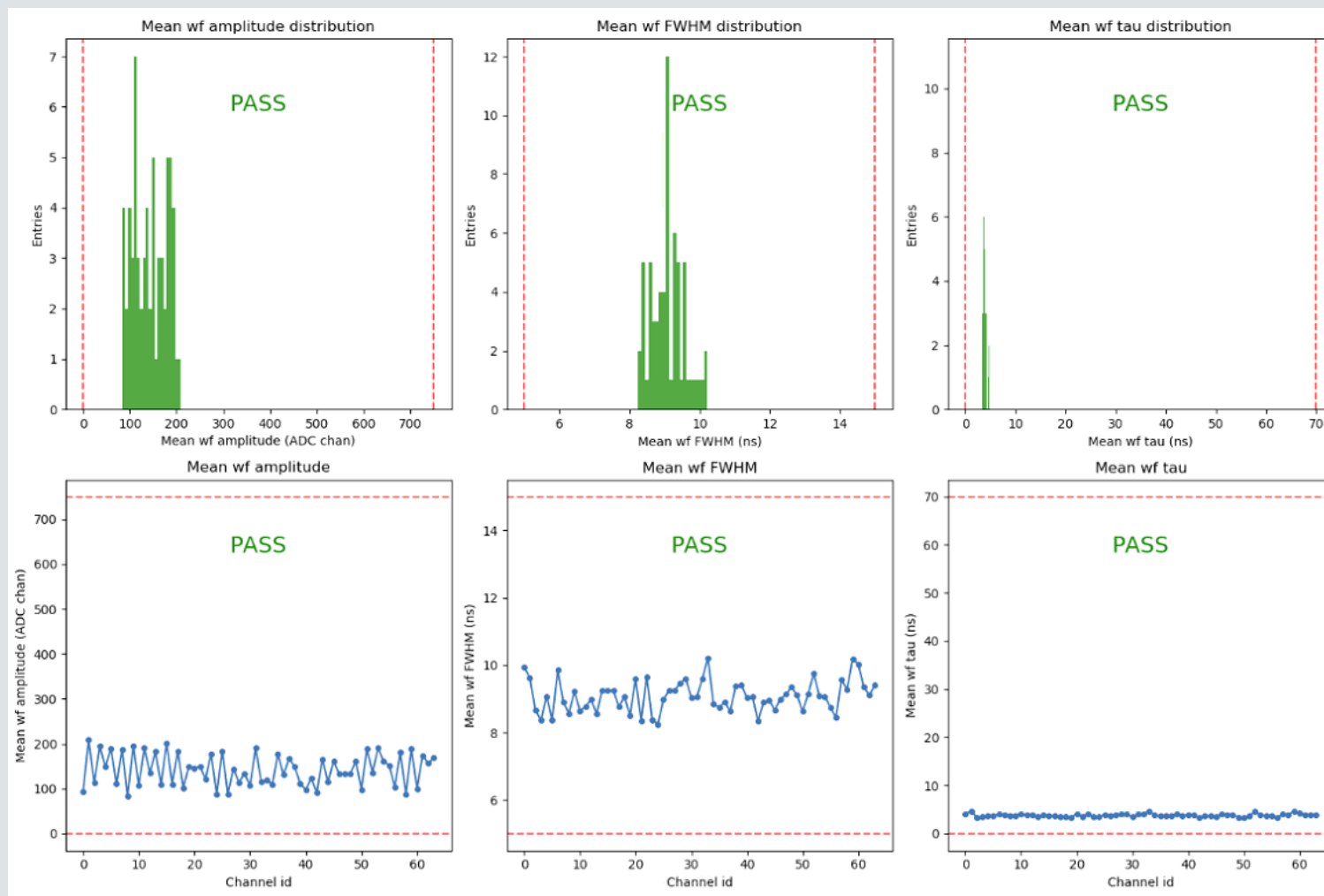
- ADC calibration for current readout
- Response to a laser pulse
- Variation of pulse shape vs SMART configuration
- Pulse amplitude variation vs DAC for fine SiPM bias tuning

See poster by G. Tripodo!



# SMART configurations loop

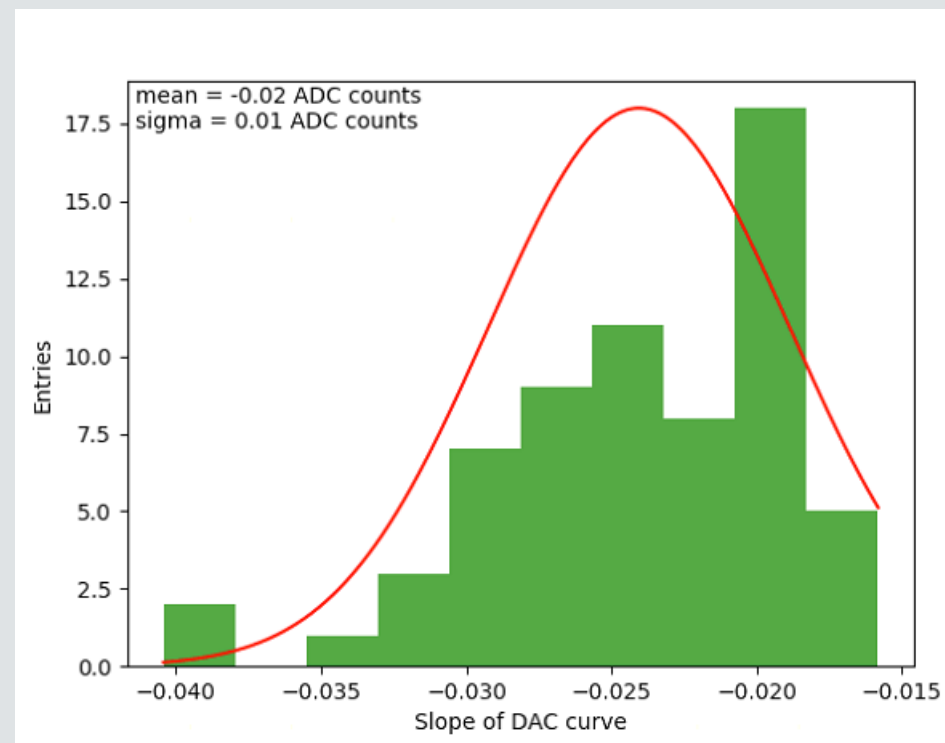
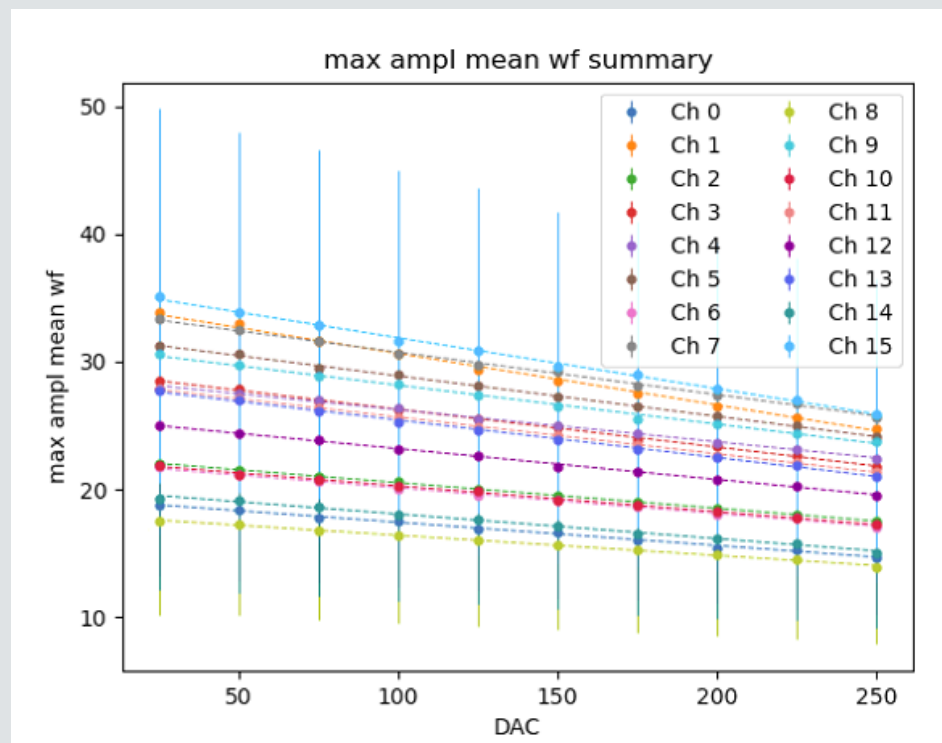
Amplitude, FWHM and tail recovery time of each channel: distribution (top) and scatter plot (bottom)





# DAC loop

Amplitude of the mean waveform vs DAC value + linear fit and slope distribution



# Flat fielding measurements

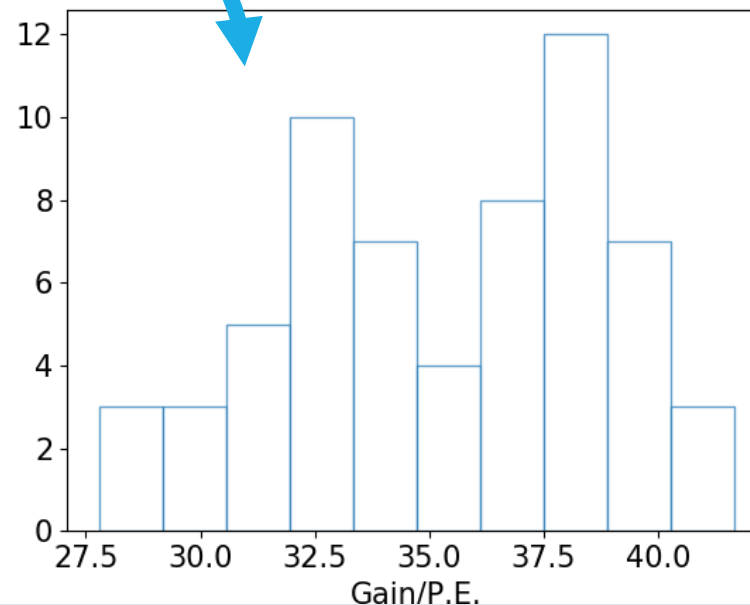
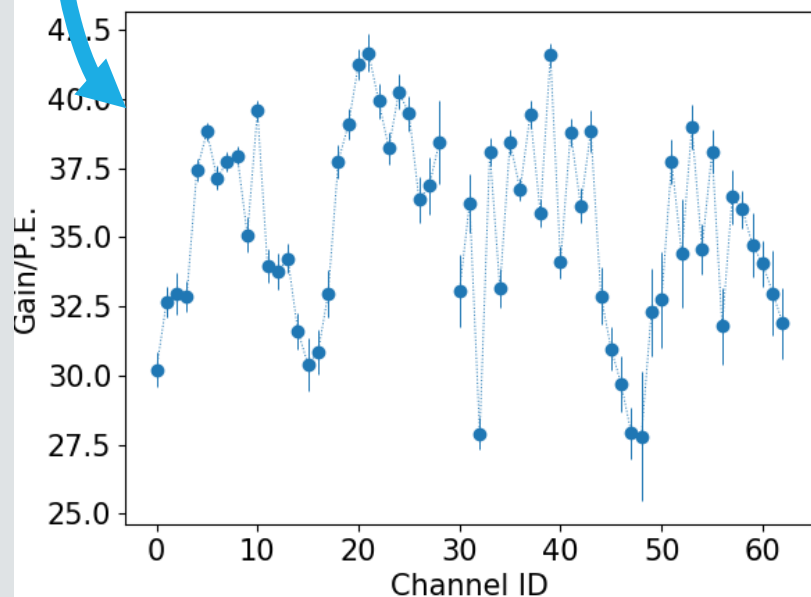
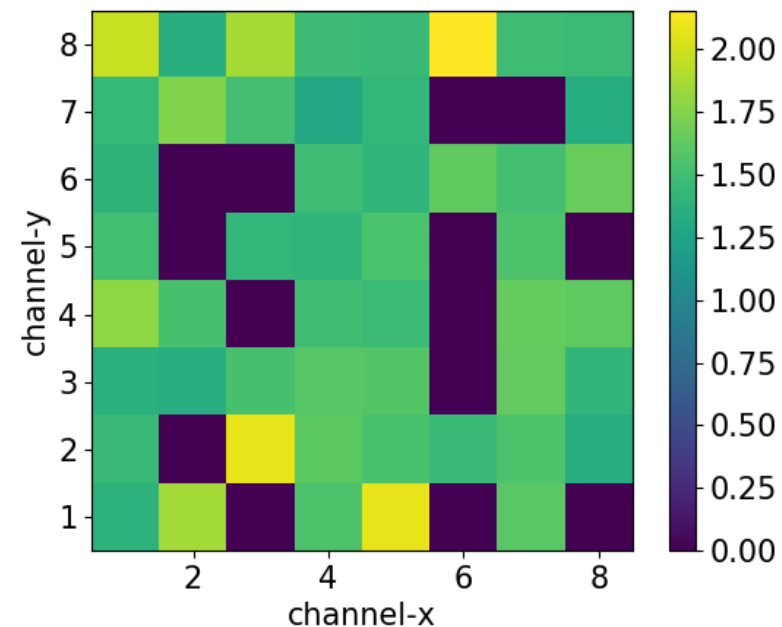
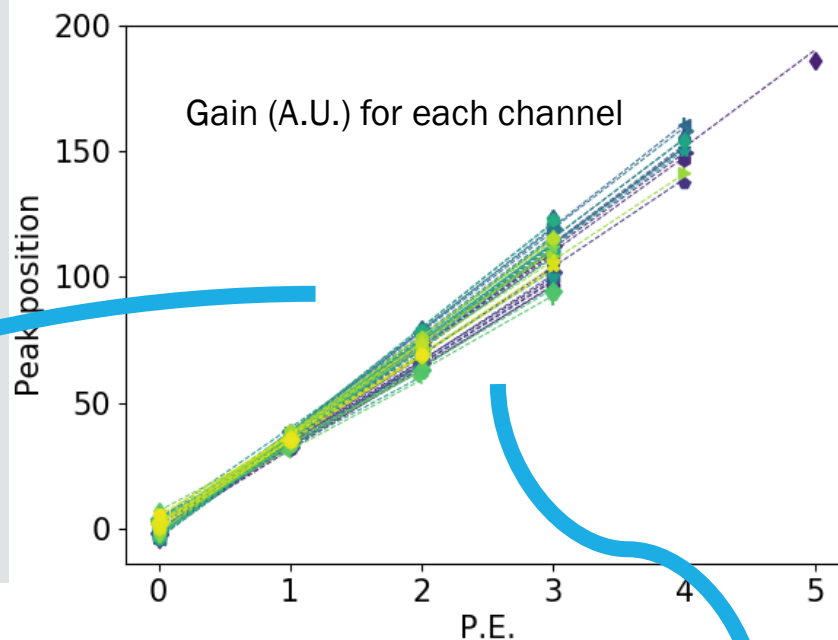
- Every SiPM in the array has its own breakdown voltage and a slightly different gain vs overvoltage dependence
- When biased at the same  $V_{\text{BIAS}}$  the overvoltages and the gains are different
- With the SMART ASIC we can change the DAC (0-255) and regulate the OV on each channel keeping the common bias voltage

DAC – OV relation:

$$\text{OV} = V_{\text{BIAS}} - V_{\text{BD}} - 0.7\text{V} - 4.7\text{mV} * \text{DAC}$$

We analyzed  
all the 64  
channels  
DAC = 100

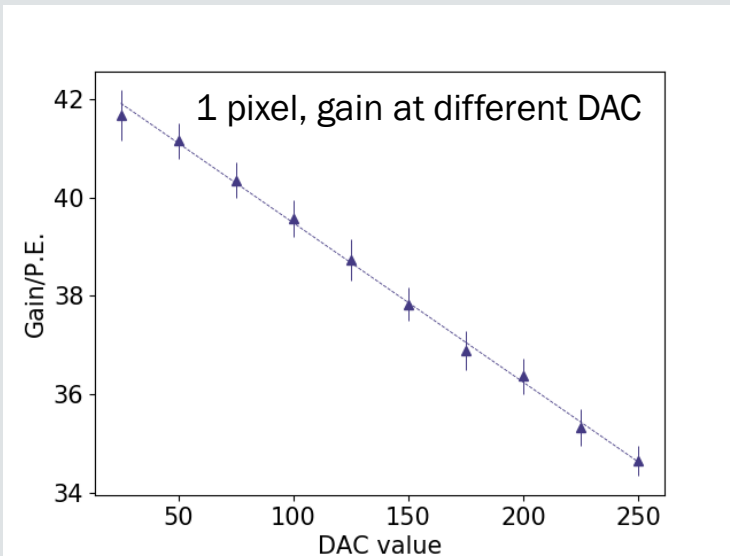
Slope of the  
best fit line



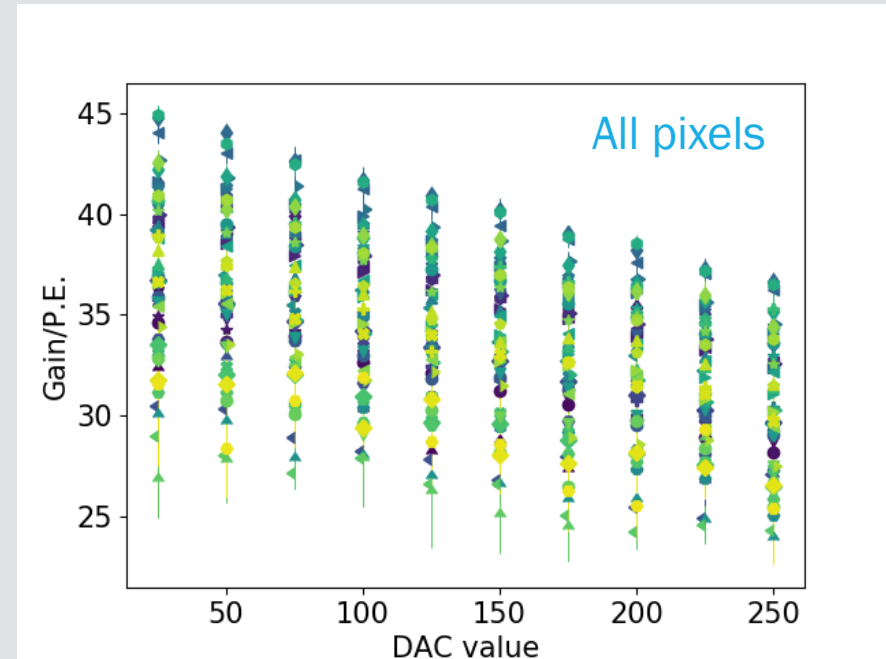
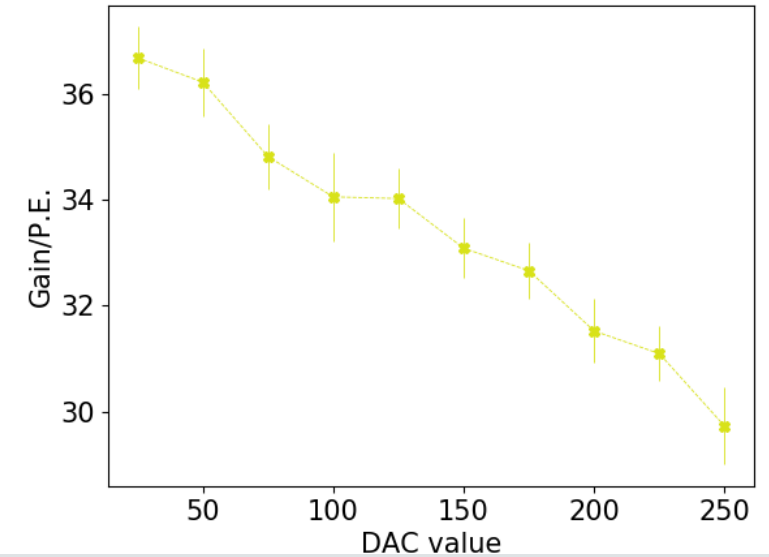
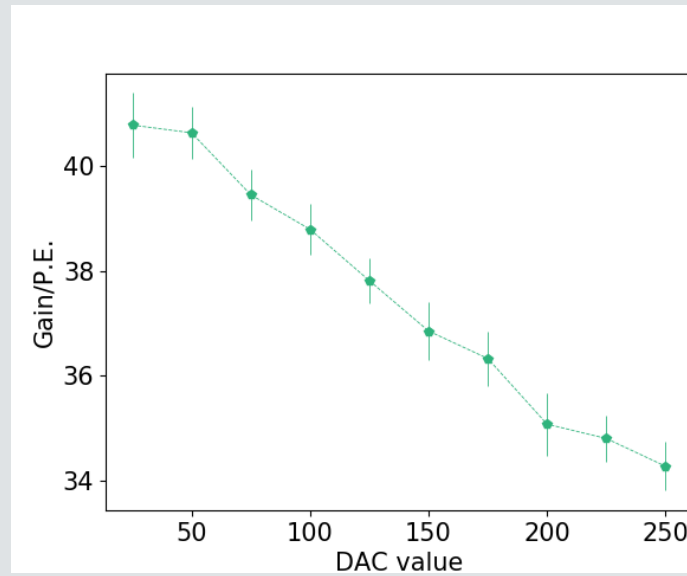
Gain/P.E. for all  
pixels:

- Scatter plot
- Distribution

# Gain vs DAC



We repeated the procedure for all the DACs tested  
Each gain vs DAC curve was fitted with a linear function



# Conclusions & Outlook

- Performances of the SMART ASIC tested and characterized with FBK NUV HD SiPMs
  - Gain and signal shape dependance on R, C and PZ
- SMART for the full pSCT camera (~750 ASICs) produced and tested in 2021
  - Only 7 ASICs were found to be defective ( $< 1\%$ )
- Studies on gain versus DAC dependance ongoing
- New design ready to be tested for future upgrades



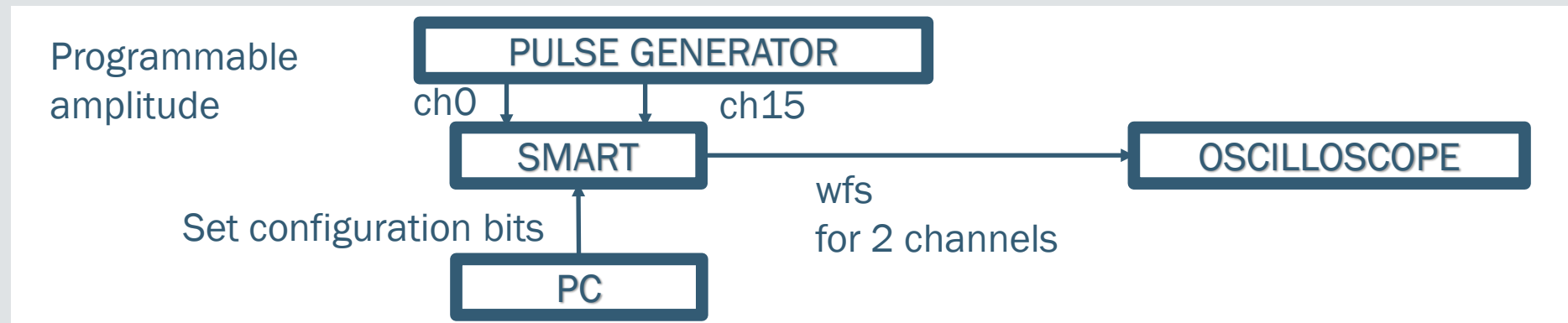
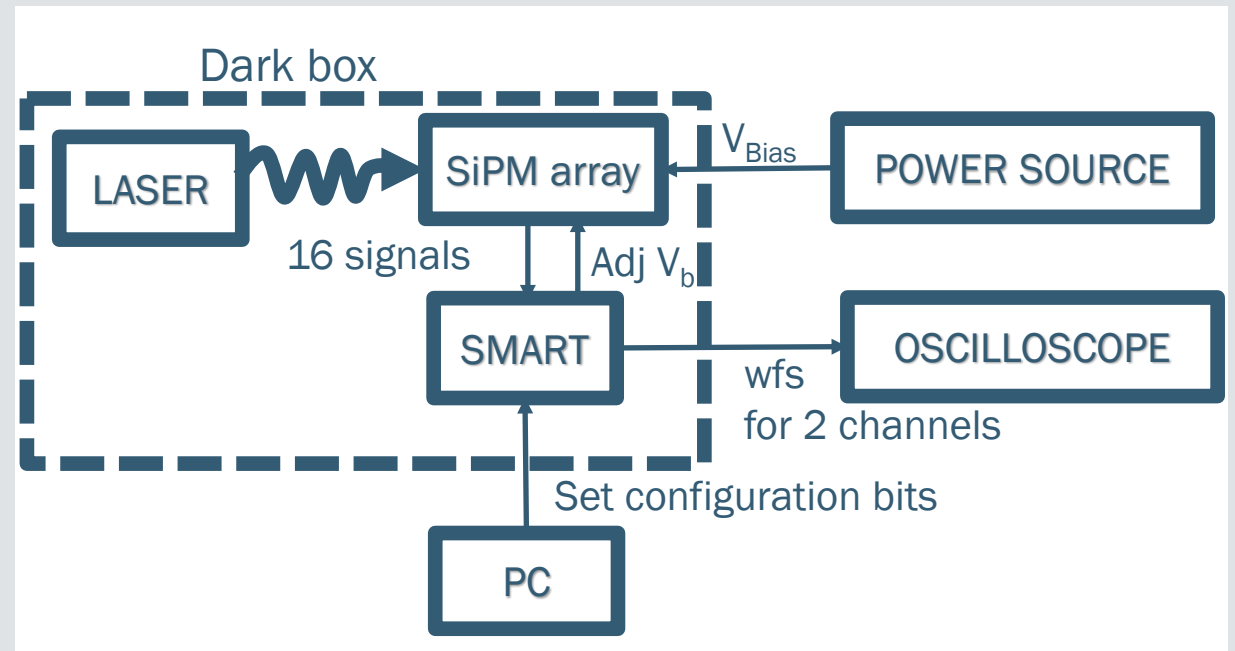
# THANK YOU!

For further information please contact  
F. Licciulli - [francesco.licciulli@ba.infn.it](mailto:francesco.licciulli@ba.infn.it)  
G. De Robertis - [Giuseppe.Derobertis@ba.infn.it](mailto:Giuseppe.Derobertis@ba.infn.it)

This work was conducted in the context of the CTA Consortium. We gratefully acknowledge financial support from the agencies and organizations listed here:  
[http://www.cta-observatory.org/consortium\\_acknowledgments](http://www.cta-observatory.org/consortium_acknowledgments)

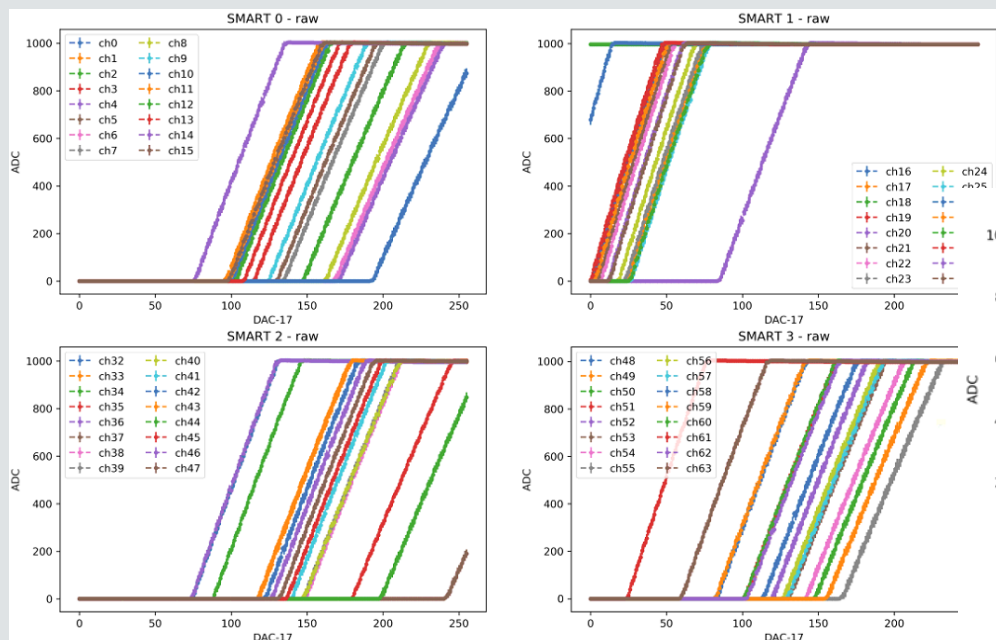
# Dynamic range

- Two independent measurements:
  - We illuminated one SiPM with high intensity pulsed light and measured the max ampl*
  - We injected in one channel a charge signal with an external pulse generator*
- We obtained the maximum waveform amplitude for different configuration bits
- We compared two channels w/ and w/o the external PZ

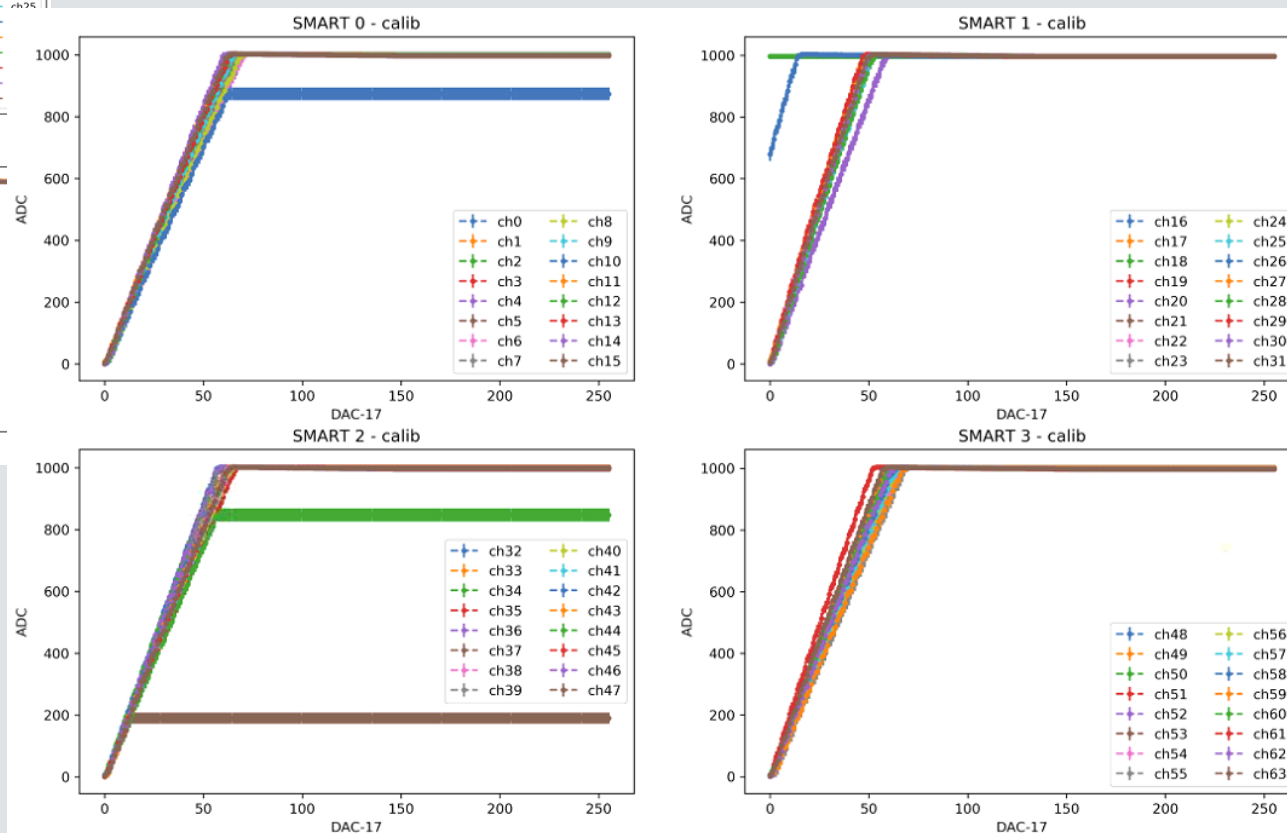


# SMART ADC Calibration

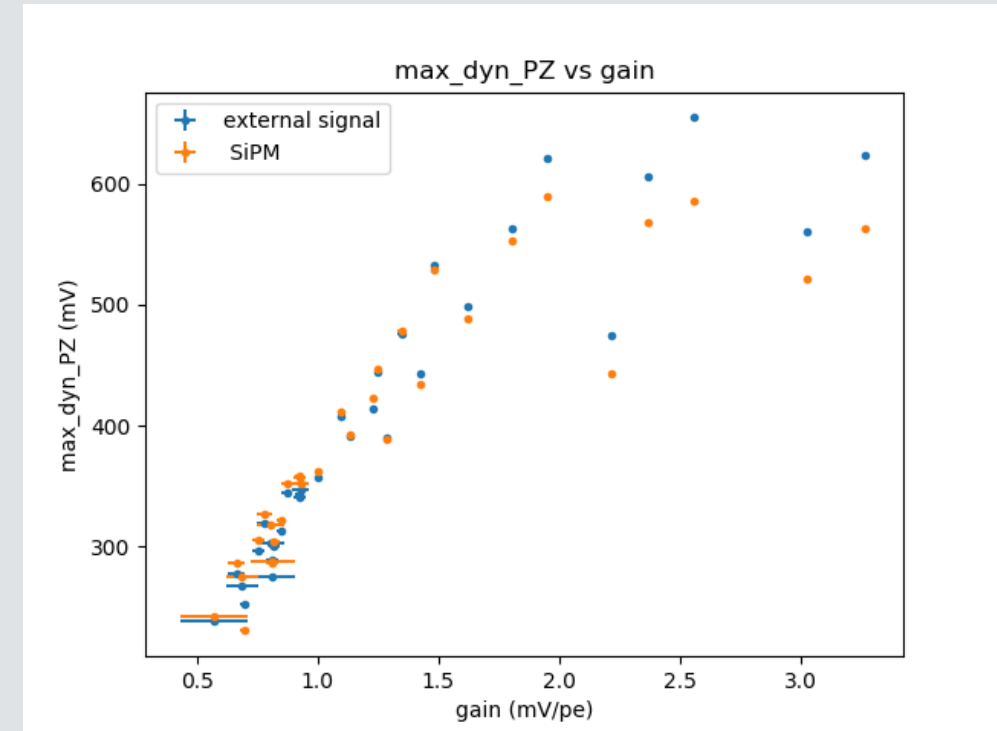
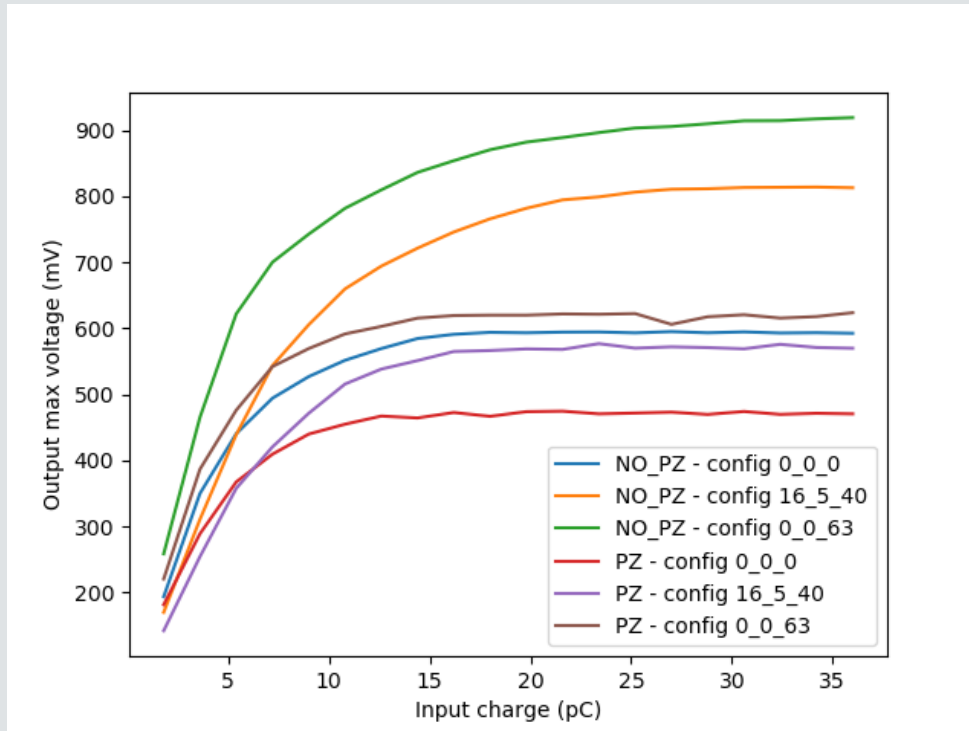
We measure the ADC value on each channel as a function of the reference channel DAC value (DAC-17).



The calibration value is stored and used to measure the  $I_{dc}$  on each channel.



# Dynamic range



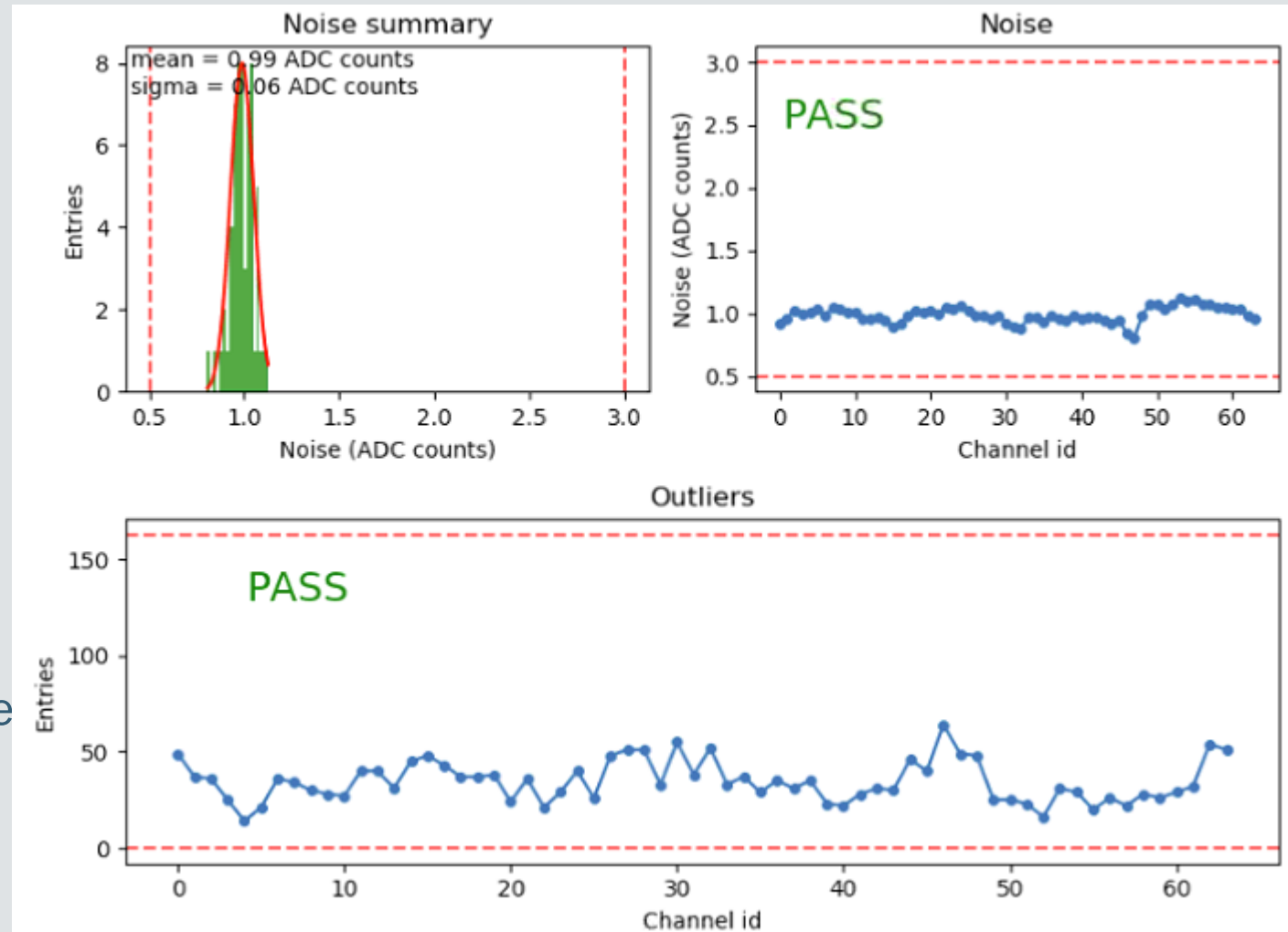
Without external PZ the maximum dynamic range is around 900mV (green).  
For an intermediate configuration (R=16,C=5,PZ=40) we reach 800 mV.  
The external PZ decreases the maximum dynamics down to 600 mV.  
For the intermediate configuration (R=16,C=5,PZ=40) it is 550 mV.

# Pedestal acquisition

## Setup:

- Trigger: hardsync
- Acquisition time: 60 s
- All buffer is scanned and pedestal is saved → used later with signal run

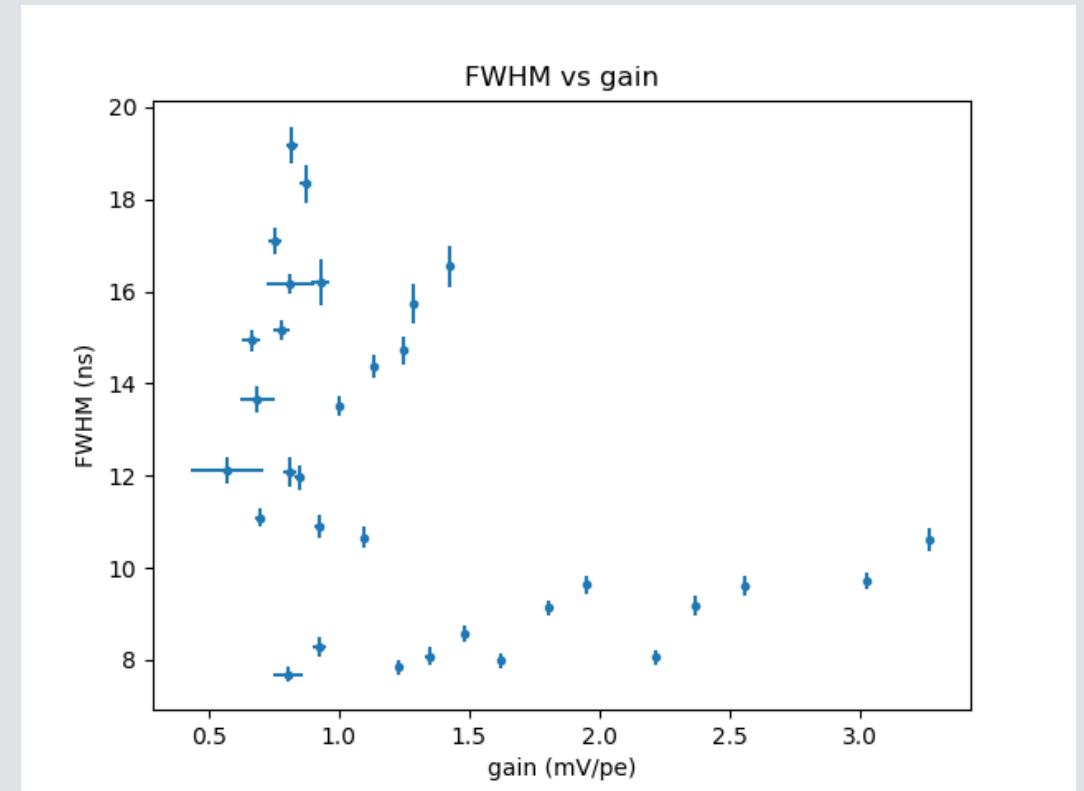
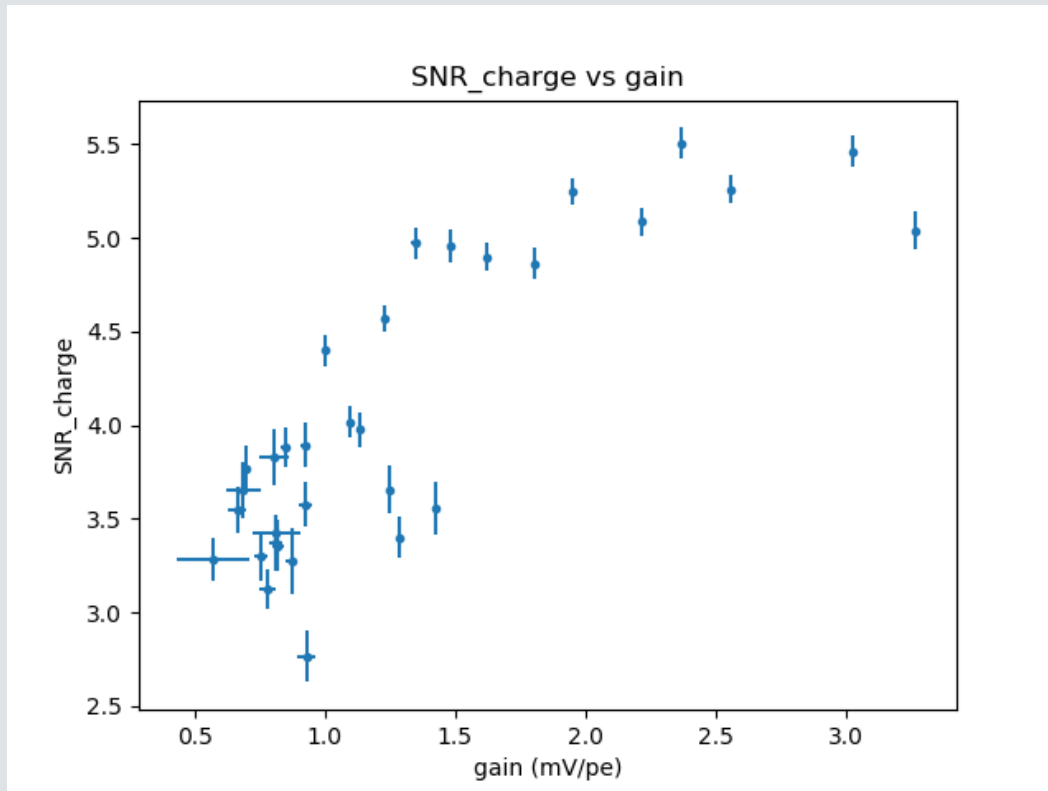
This pedestal is used to calibrate the following runs





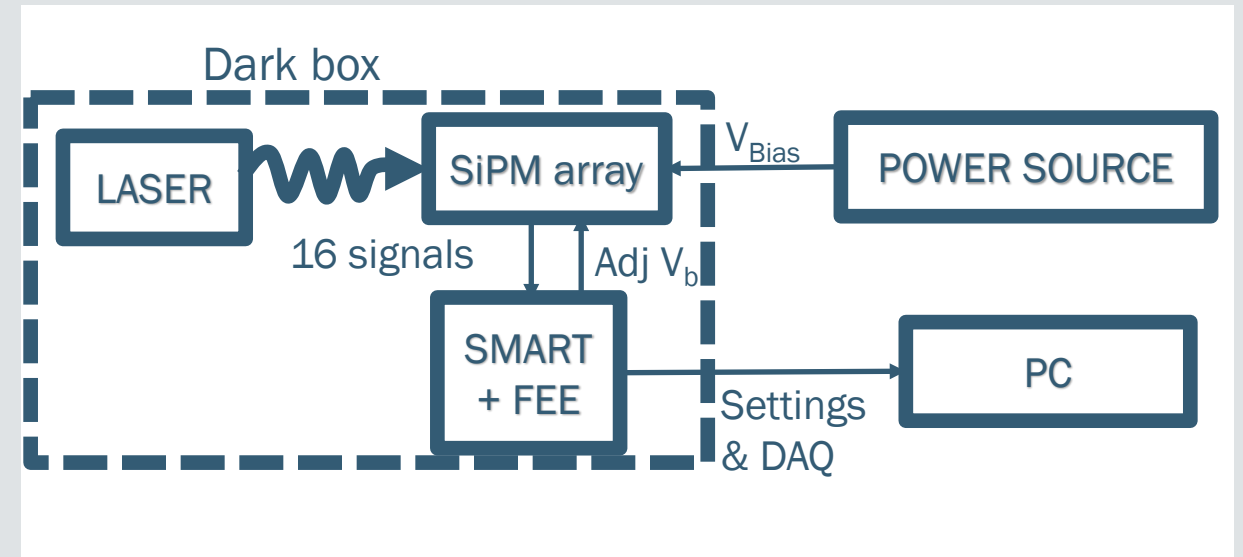
# Global configuration – Summary

$$V_{\text{Bias}} = 33 \text{ V}$$



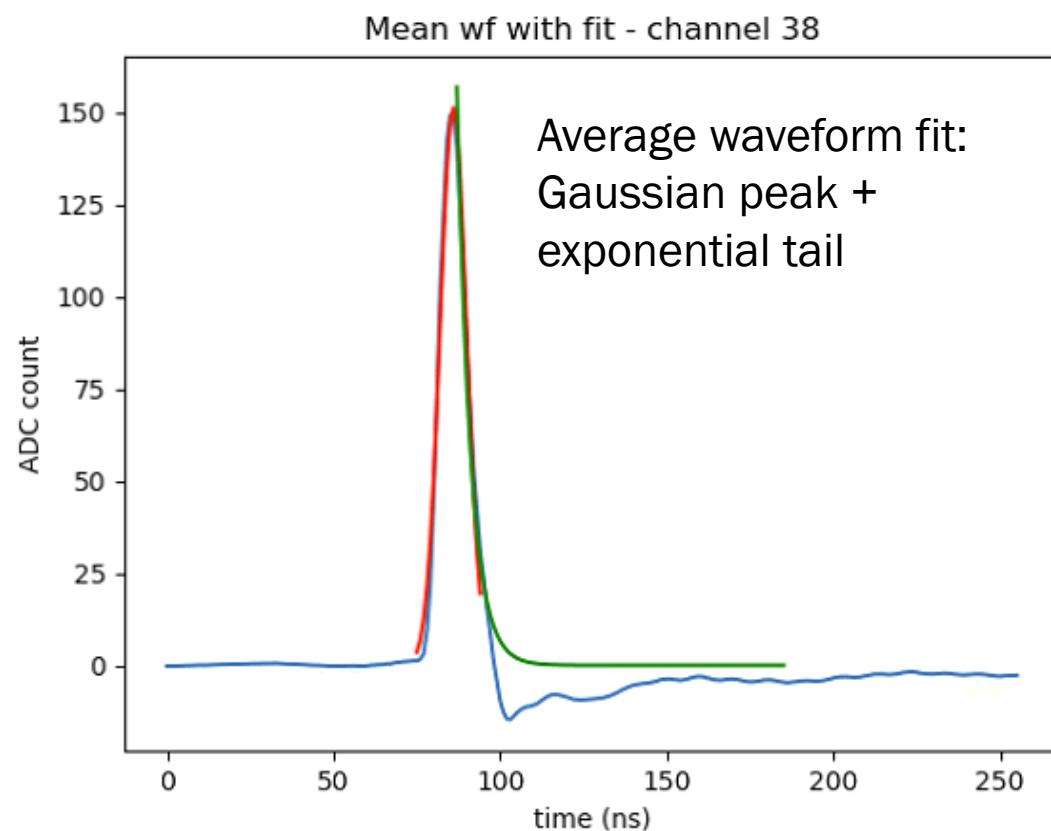
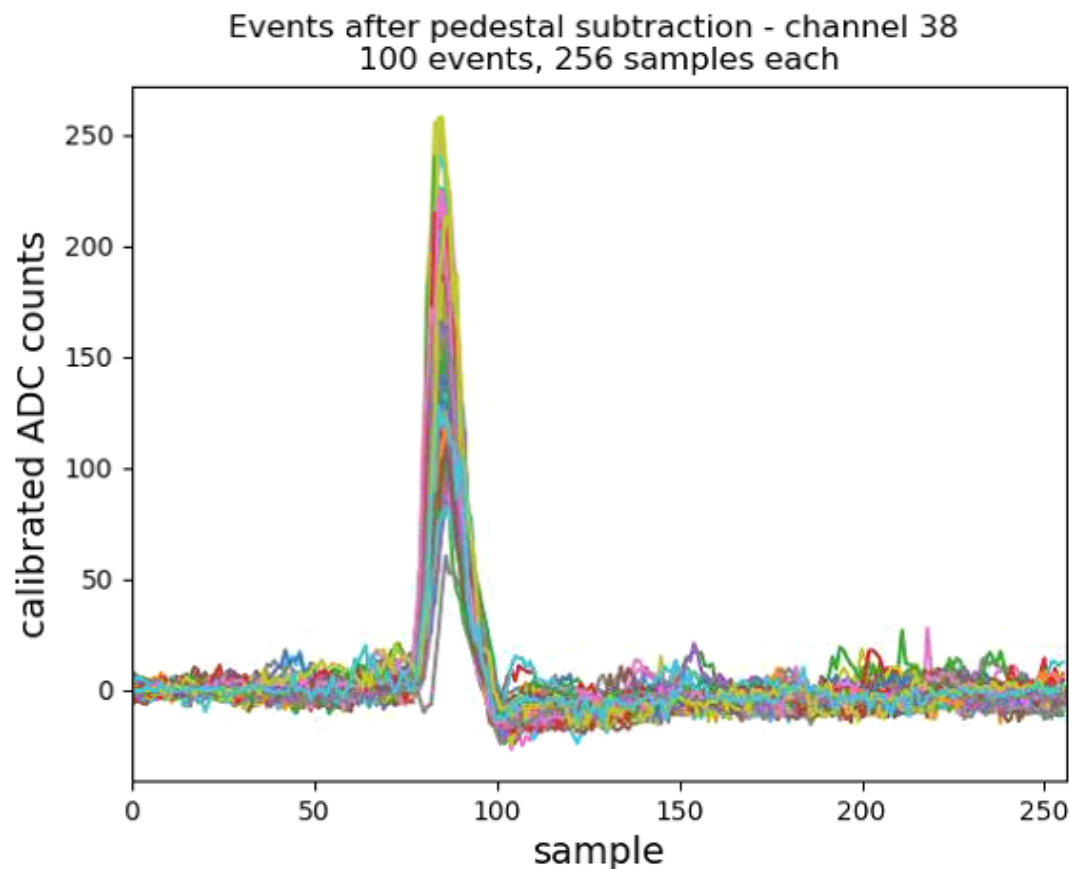
# Experimental setup

- Laser far away from SiPM arrays, diffusing lens placed in between to achieve uniform illumination
- SiPM arrays + SMART + FEE module
- 0 0 63 globals configuration to increase gain
- Low light intensity to be able to perform charge integrated spectrum
- $V_{BIAS}$  fixed to 33.5 V
- 10s acquisition time (about 10k wfs)
- Scan on DAC value to change the OV
  - *At first, DAC is the same on all channels*
- Charge distribution
- Multigaussian fit → gain and mean p.e.



# Signal run

10 s acquisition time with external trigger, laser on all pixels (almost uniform)



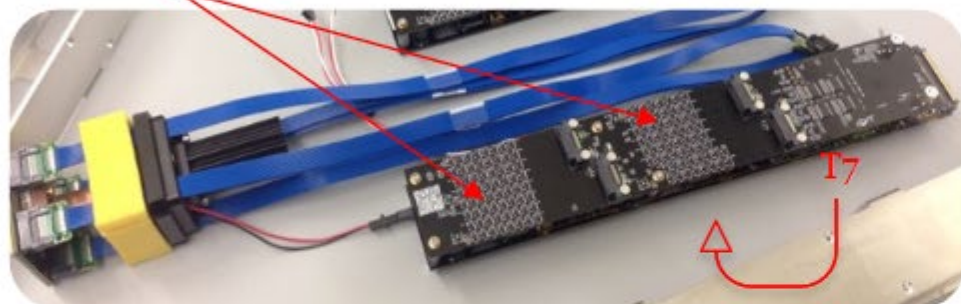
# Upgrade of the camera

- Populate all 9 camera sectors → 177 modules – 11328 pixels
- SiPMs produced by FBK with high PDE and low optical CT
- New electronics to reduce noise
  - Separation of the digitizing and trigger ASICs (TARGET-C + T5TEA)
  - Integrated pre-amplifier attached to SiPM boards (SMART)
- New DACQ boards
- New module cage
- New camera frame and redesign of the cooling system

# Full-chain testing : current vs. upgrade

M. Capasso's talk @  
CTA Consortium  
Meeting May 2021

Preamps and current  
sensors



FPM

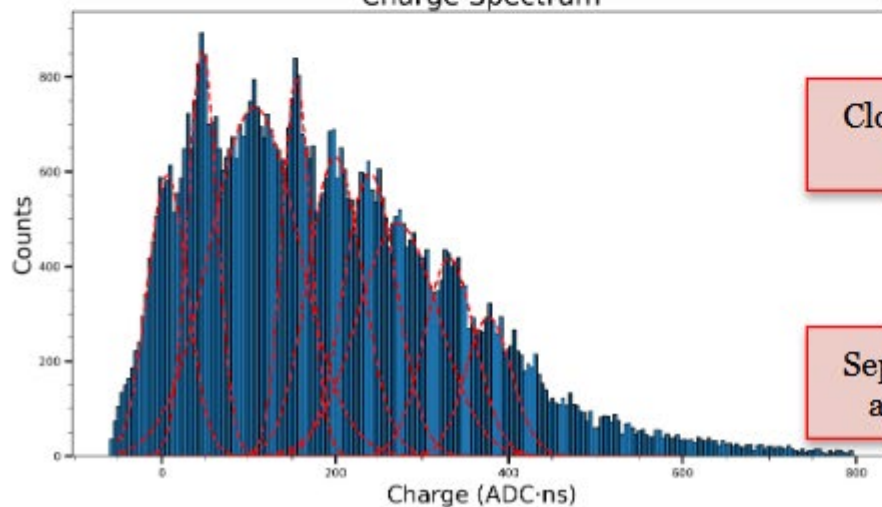


FPM+preamps  
and current  
sensors (SMART)

(C)T<sub>5</sub>TEA + (C)TC



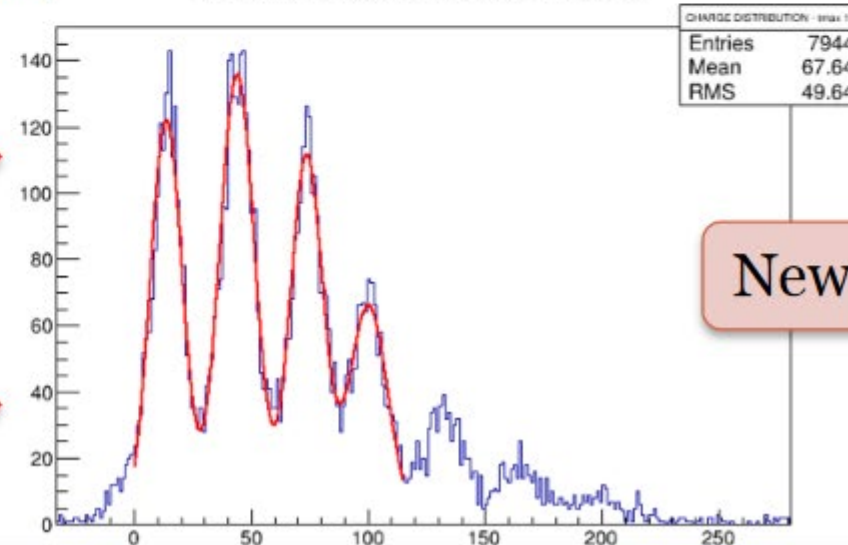
Charge Spectrum



Closer FPM and  
preamps

Separate trigger  
and digitizer

CHARGE DISTRIBUTION - tmax 10

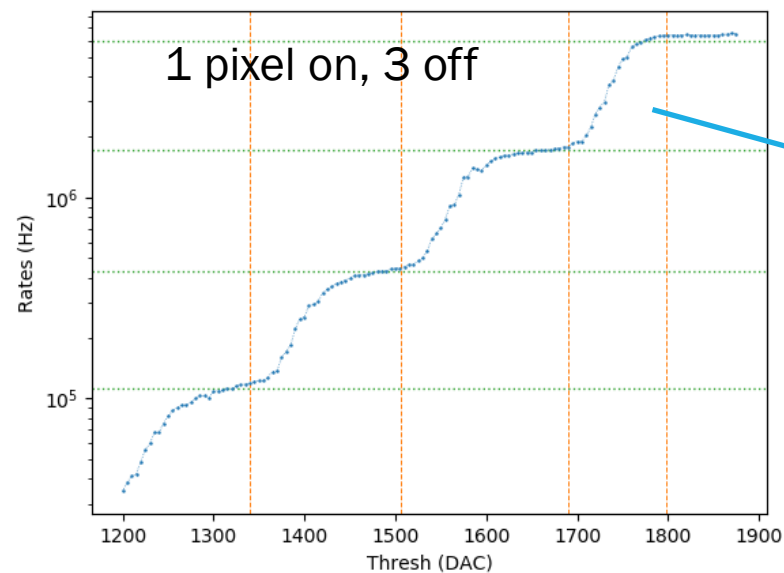
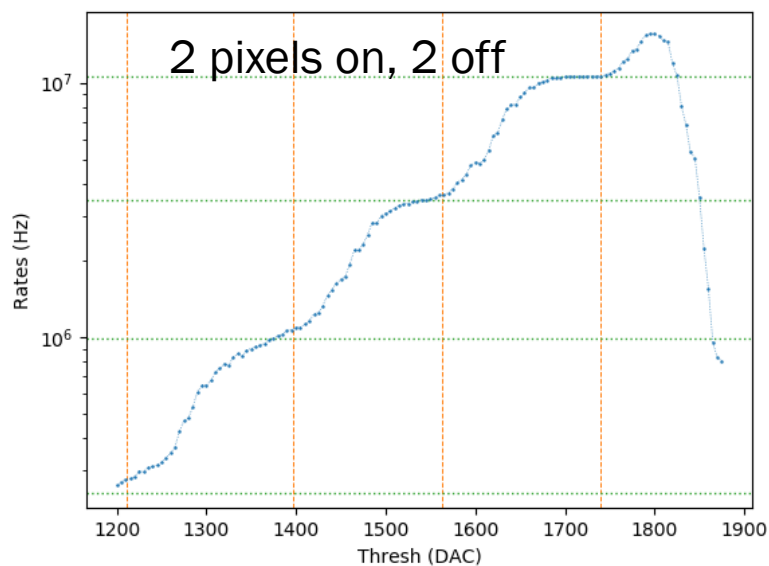
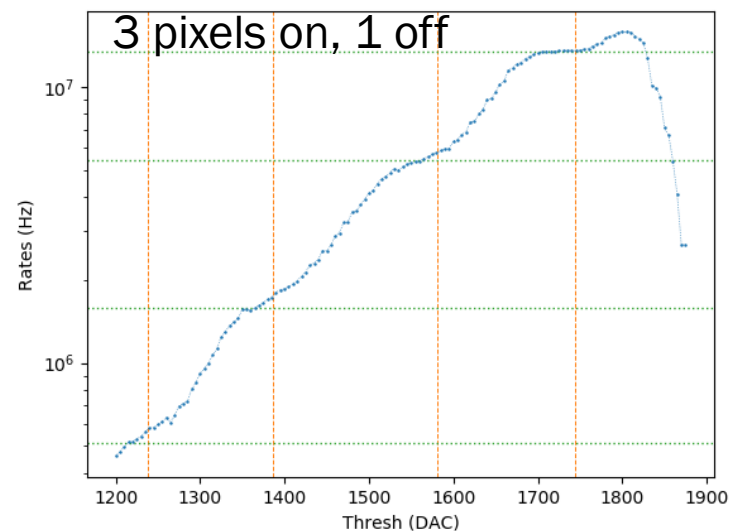


New



# Trigger scan

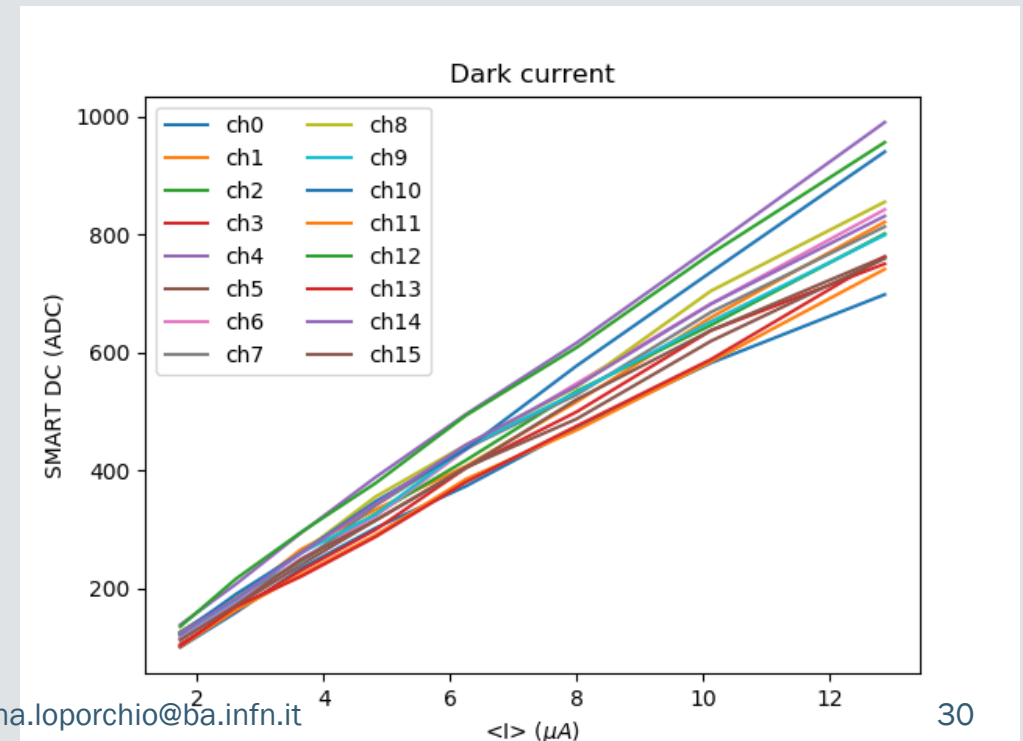
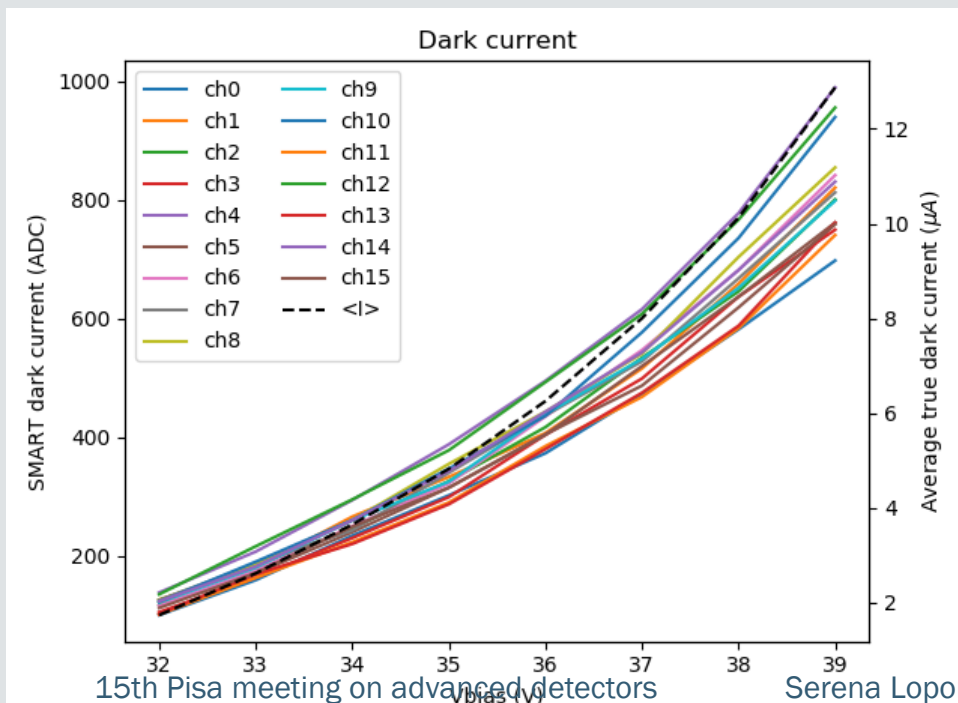
- We performed a scan in threshold value trigger on one trigger group
  - We performed the scan disabling 1, 2 and 3 pixels (i.e., triggering on 3, 2, and 1 pixels) *using the SMART control registers*



We can determine the DAC count / p.e. on each pixel

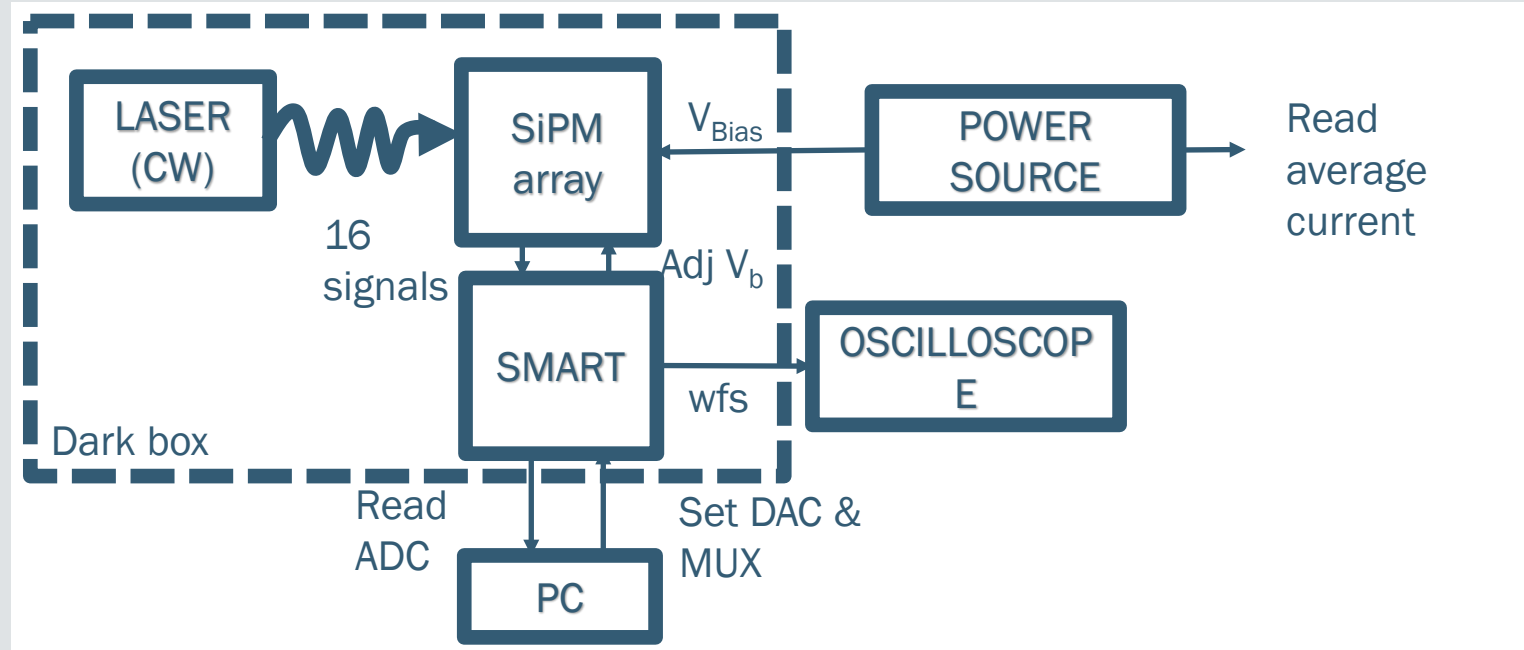
# Slow control

- We measure the DC current on each channel in dark conditions as a function of bias voltage
  - For each  $V_{bias}$  and each channel we set the DAC on ch 17 found from calibration (previous slide) and measure the mean current with the ADC
  - We compare the ADC current with the average dark current measured with the power meter



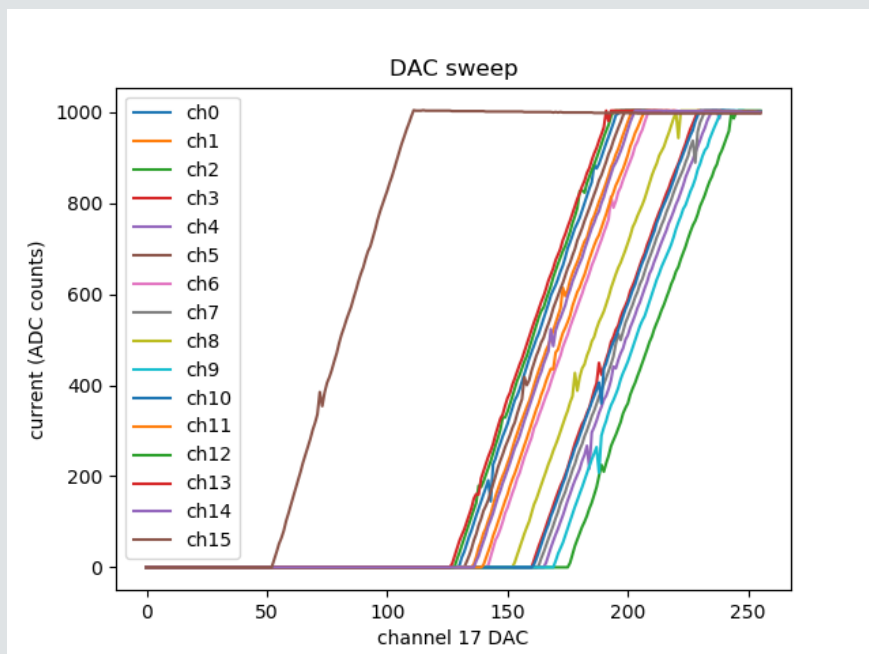
# Slow control - setup

- Configuration is fixed  $R=16, C=5, PZ=40$
- DC current is measured for each channel using a reference channel (ch 17)
- The reference channel has a configurable DAC which should be set accordingly for each channel
- DC current measured for different bias voltages in dark conditions and for fixed bias voltage with increasing light illumination

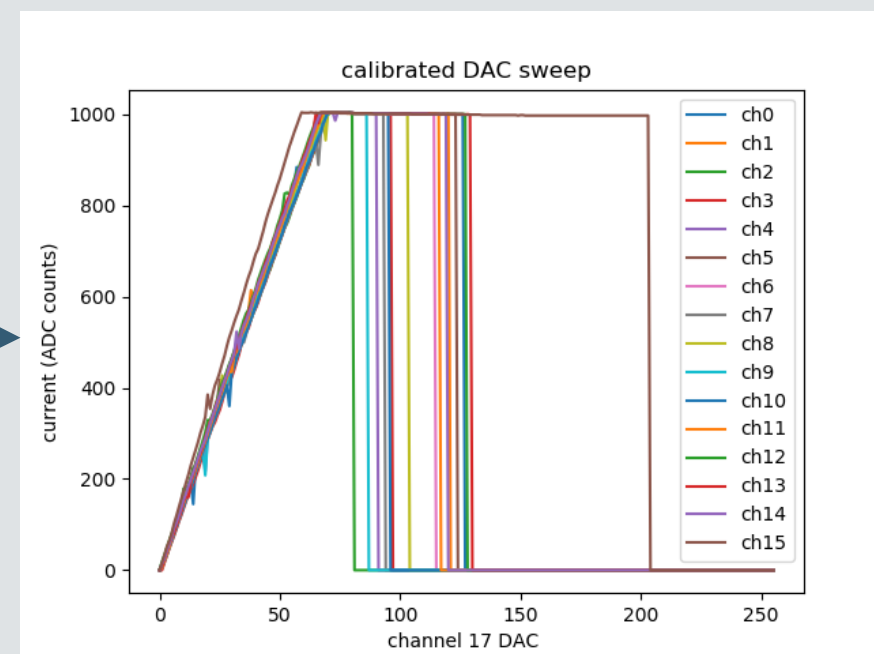


# Slow control

- We connect the SiPMs to the SMART and keep  $V_{\text{bias}} < V_{\text{breakdown}}$
- For each channel (ch0-ch15) we loop over DAC value for ch17
  - *The optimal value ('calibration' value) is obtained when the ADC value becomes larger than 0*

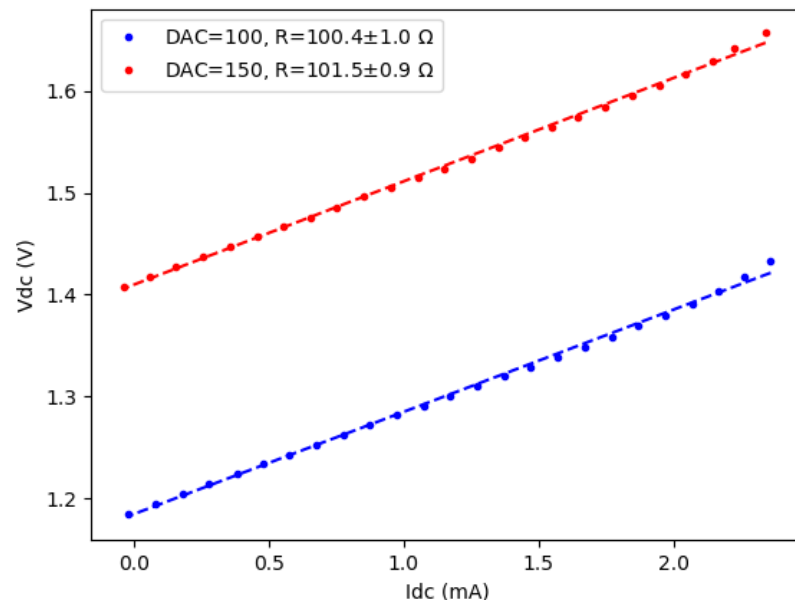
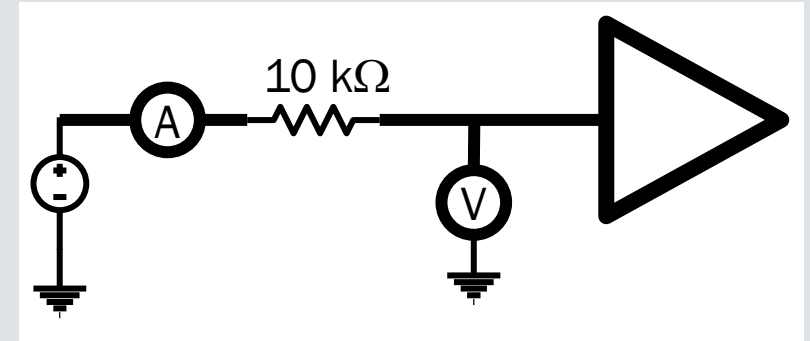


DAC 'calibration'



# Internal resistance

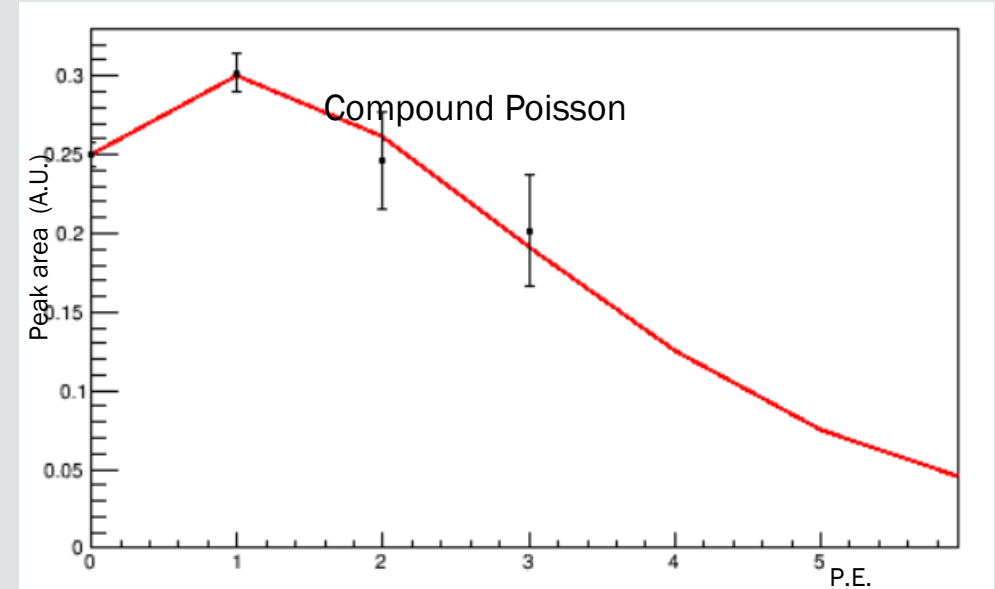
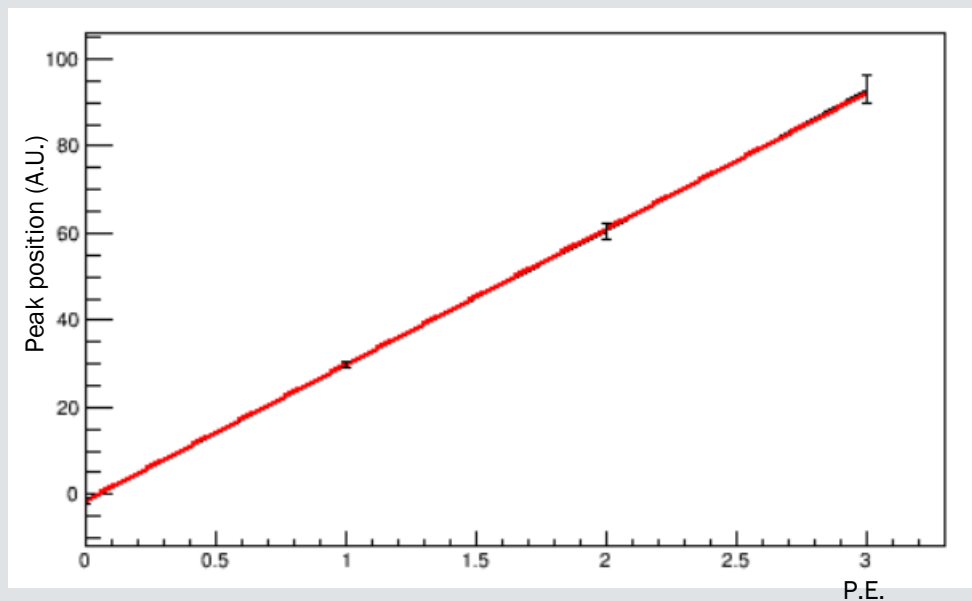
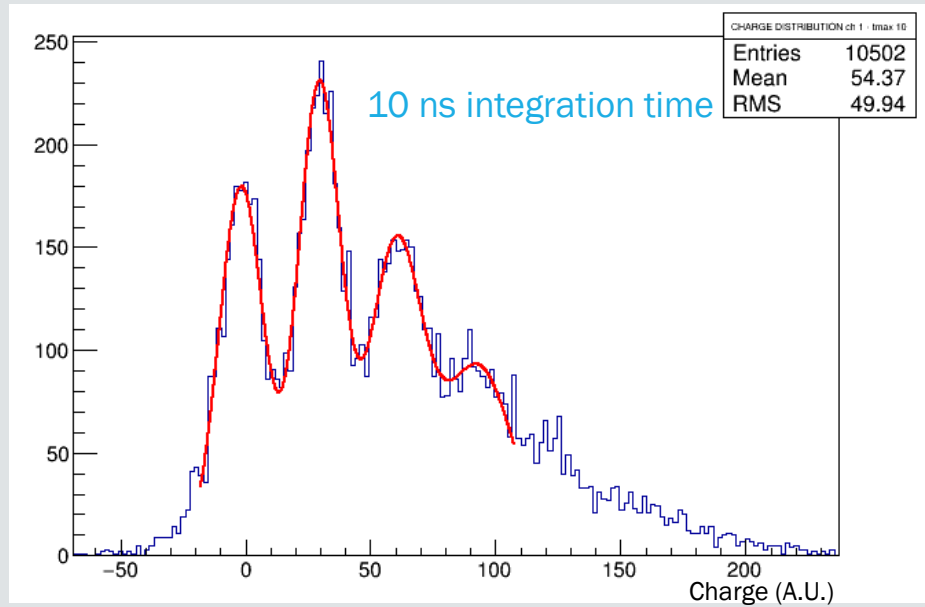
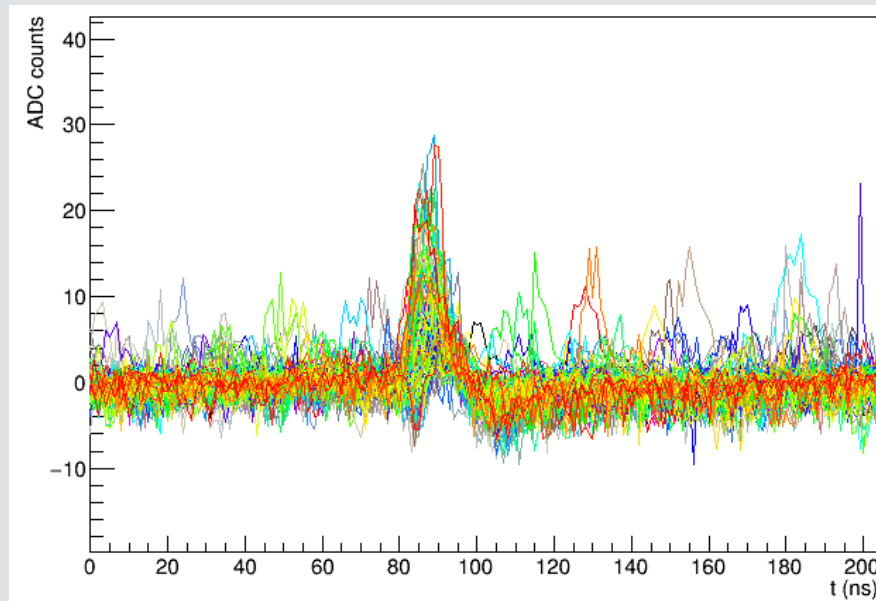
- We connected the input of channel 0 to a voltage source with a series resistance
- We changed the input voltage and measured the injected current and the voltage at the input of the SMART channel



Resistance is approximately  $100 \Omega$   
The different DAC settings change the absolute voltage values but not the slope

The channel was tested injecting a current up to 2.35mA without any damage

1 pixel  
DAC = 100



# SMART configurations loop

Amplitude, FWHM and tail recovery time of each channel reported for 4/10 configurations

Good uniformity among channels for a fixed configuration

